

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz;Duty Cycle: 1:1.015
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

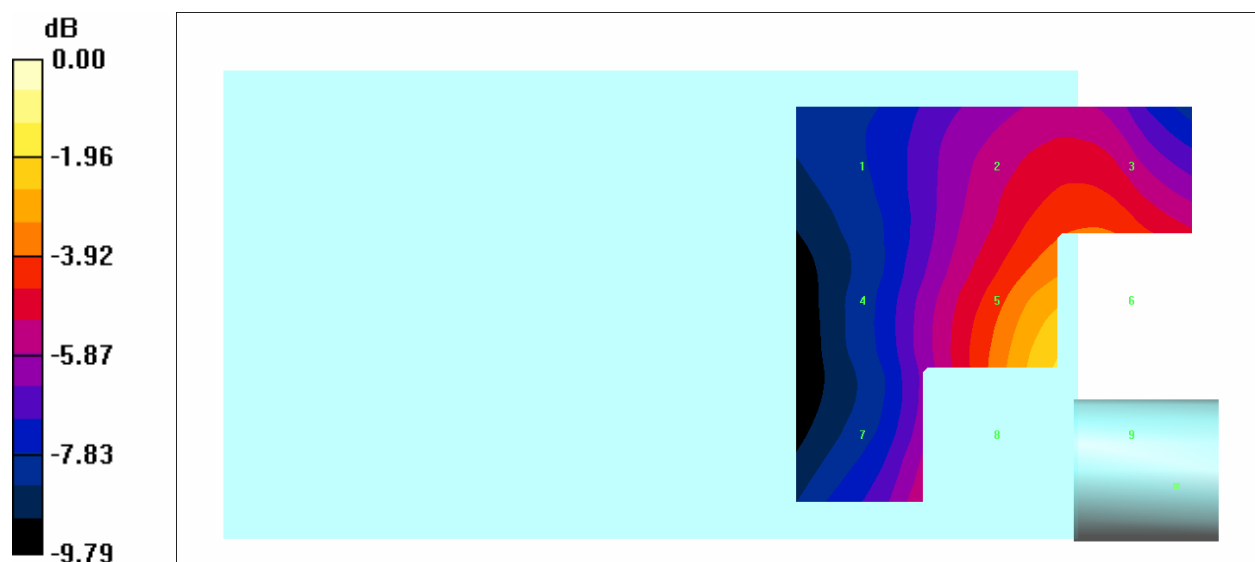
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Low/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 84.5 V/m
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
47.4	65.6	67.1	47.7	66.1	67.6
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
51.0	83.9	89.3	51.4	84.5	90.0
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
56.2	93.0	103.8	56.7	93.7	104.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 103.8V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz;Duty Cycle: 1:1.015
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

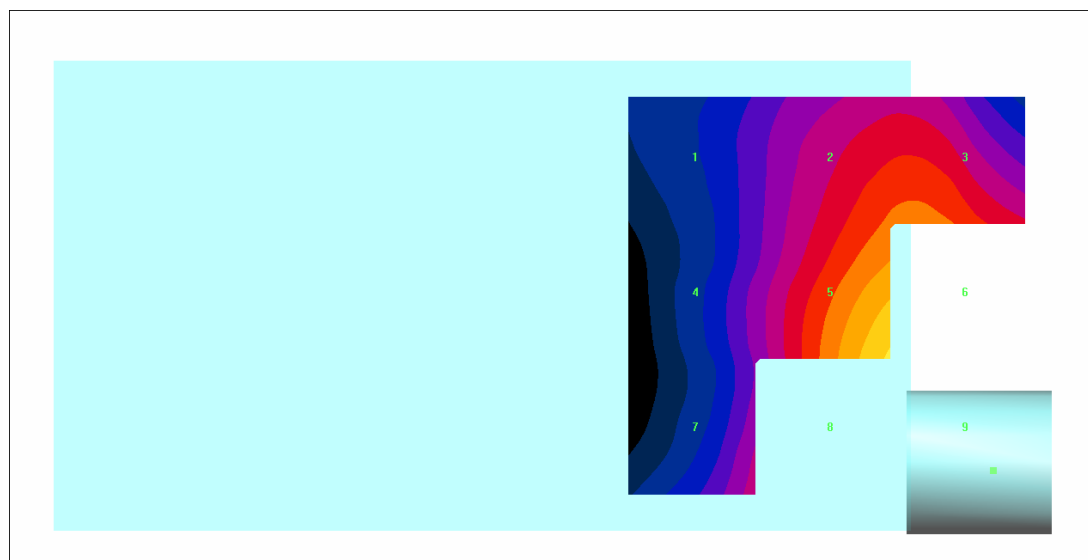
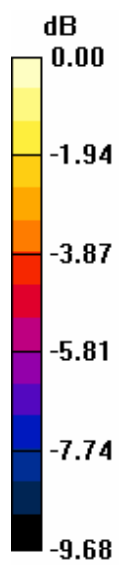
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 87.6 V/m
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
49.7	69.8	71.3	50.1	70.3	71.8
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
52.7	87.0	92.9	53.1	87.6	93.6
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
57.4	95.9	106.7	57.8	96.6	107.5

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 106.7V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High/Hearing Aid Compatibility Test

(101x101x1): Measurement grid: dx=5mm, dy=5mm

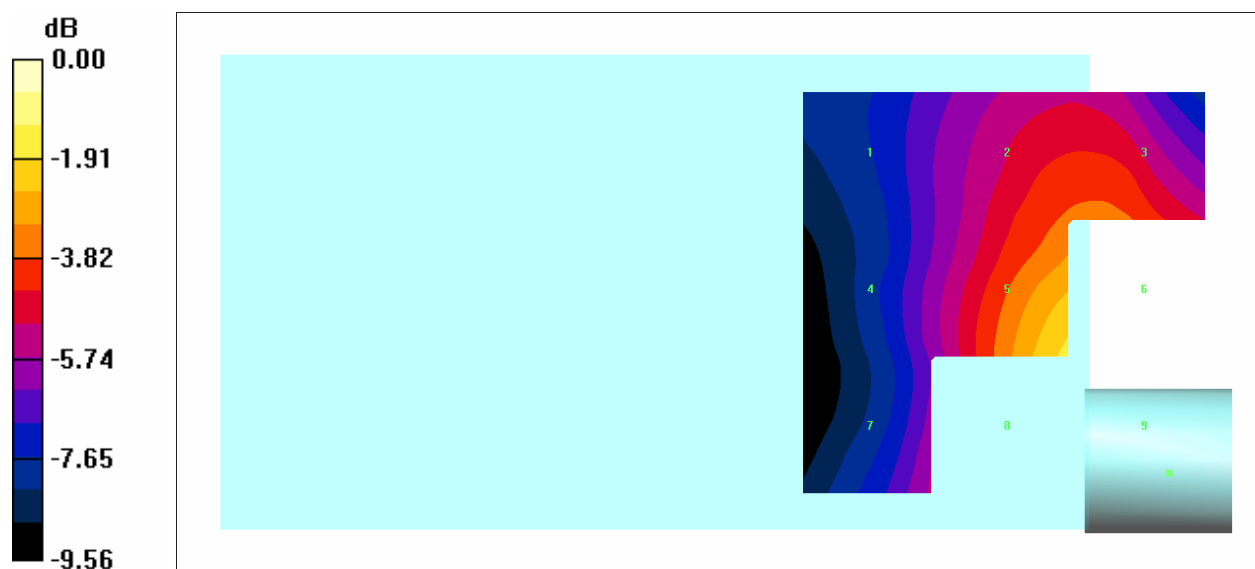
Maximum value of Total field (slot averaged) = 87.3 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
50.6	69.0	70.1	51.0	69.5	70.6
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
52.8	86.7	92.0	53.2	87.3	92.7
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
55.5	93.9	105.3	56.0	94.6	106.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 105.3V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Low with co-location/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

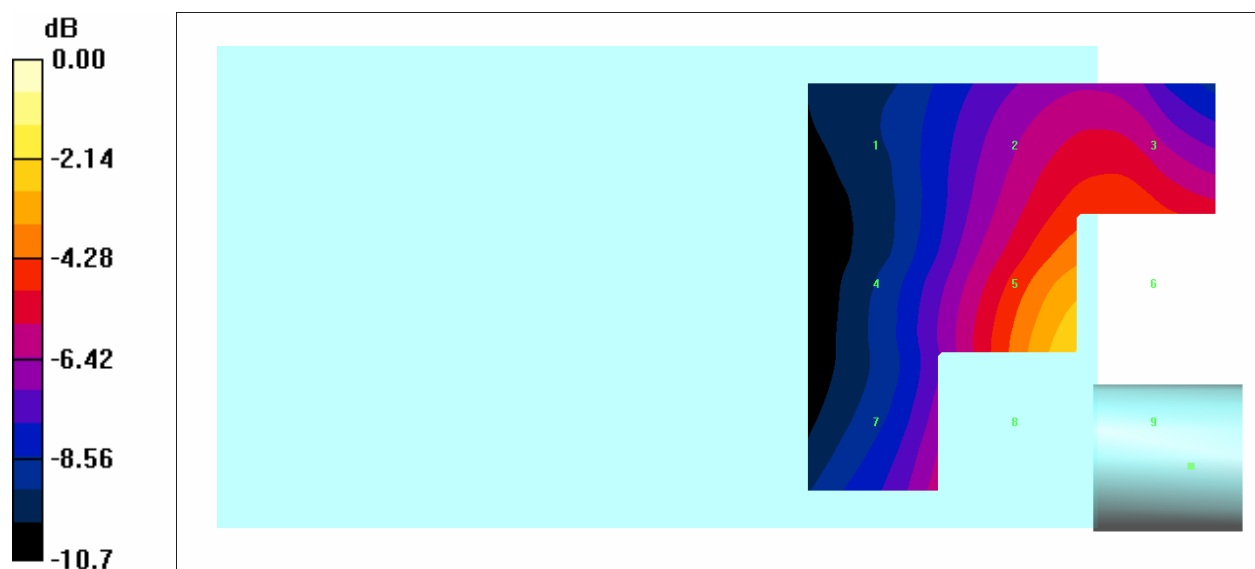
Maximum value of Total field (slot averaged) = 86.2 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 43.1	Grid 2 64.6	Grid 3 66.6	Grid 1 43.5	Grid 2 65.1	Grid 3 67.1
Grid 4 48.3	Grid 5 85.5	Grid 6 93.7	Grid 4 48.7	Grid 5 86.2	Grid 6 94.4
Grid 7 54.4	Grid 8 94.5	Grid 9 108.8	Grid 7 54.8	Grid 8 95.2	Grid 9 109.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 108.8V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz;Duty Cycle: 1:1.015
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

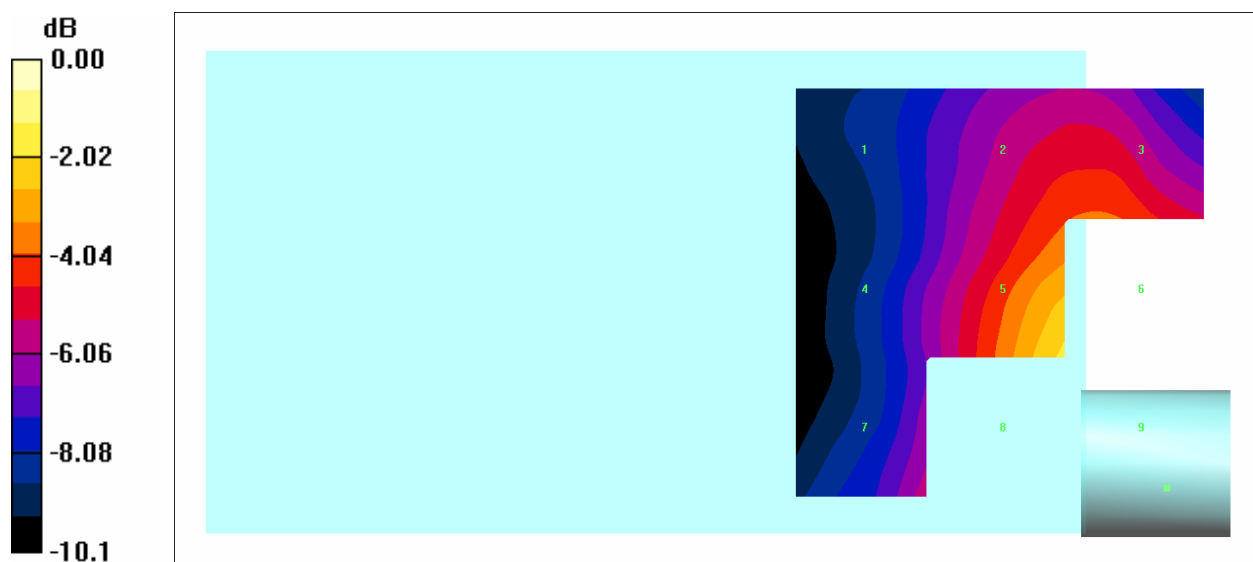
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid with co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 89.7 V/m
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
47.0	68.5	70.1	47.4	69.0	70.6
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
51.8	89.1	95.2	52.2	89.7	96.0
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
57.3	97.3	109.7	57.7	98.0	110.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 109.7V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High with co-location/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

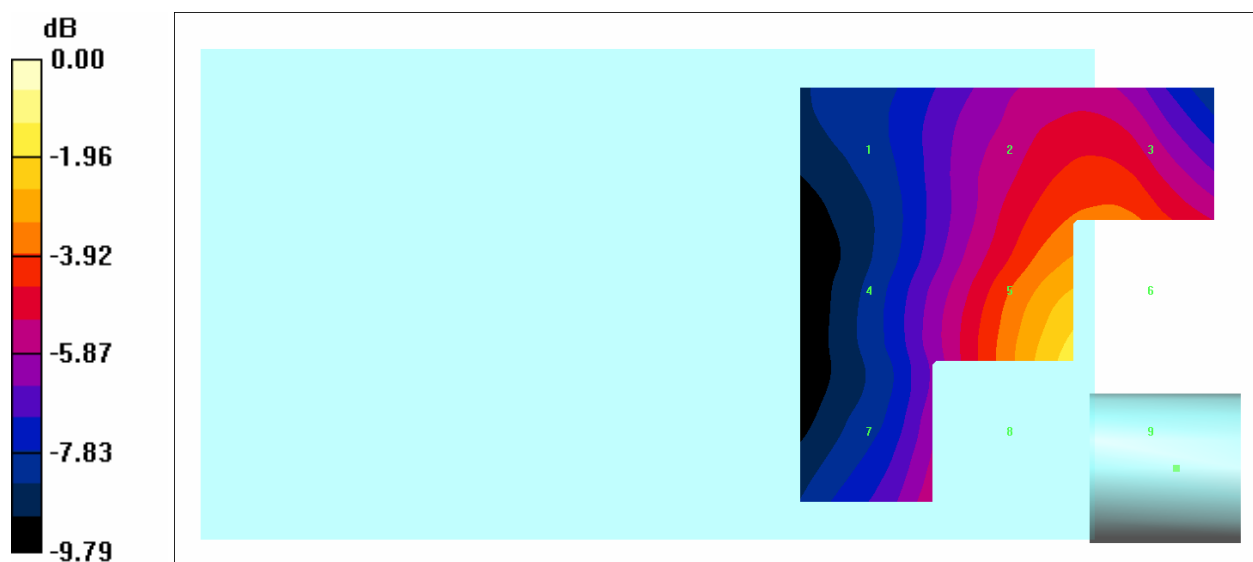
Maximum value of Total field (slot averaged) = 87.5 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 46.9	Grid 2 67.1	Grid 3 68.5	Grid 1 47.2	Grid 2 67.6	Grid 3 69.0
Grid 4 51.3	Grid 5 86.8	Grid 6 92.2	Grid 4 51.7	Grid 5 87.5	Grid 6 92.9
Grid 7 56.1	Grid 8 95.1	Grid 9 104.2	Grid 7 56.5	Grid 8 95.8	Grid 9 105.0

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 104.2V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz; Duty Cycle: 1:1.01

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Low/Hearing Aid Compatibility Test

(101x101x1): Measurement grid: dx=5mm, dy=5mm

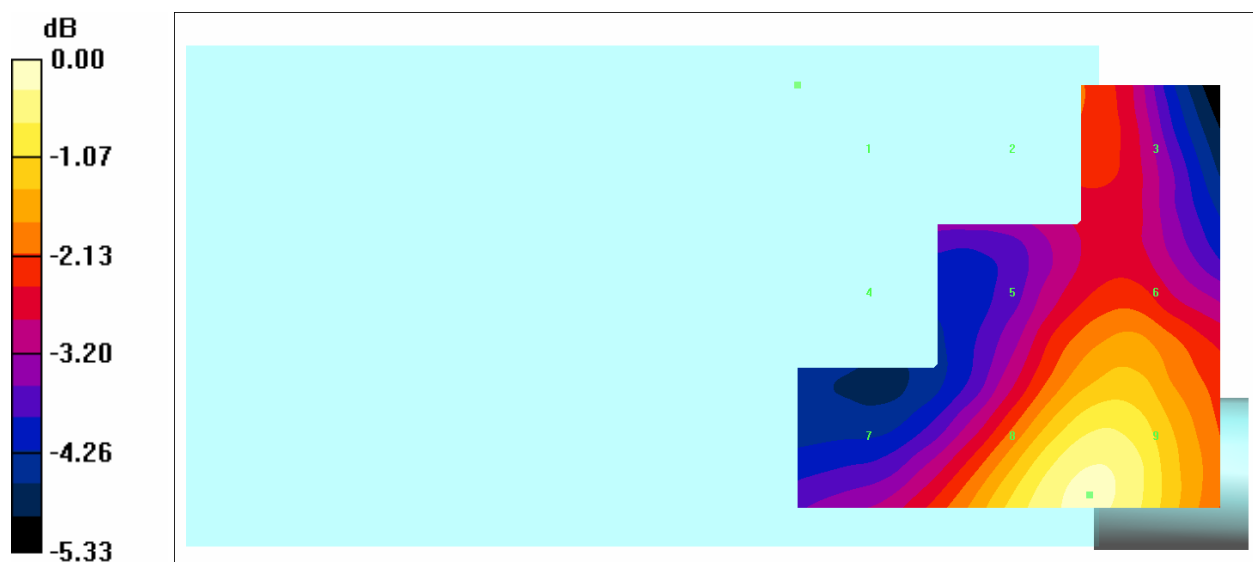
Maximum value of Total field (slot averaged) = 56.9 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
58.2	51.5	45.8	58.5	51.7	46.0
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
45.8	47.3	49.3	46.0	47.6	49.6
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
44.3	56.5	56.6	44.5	56.7	56.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 58.2V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz; Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

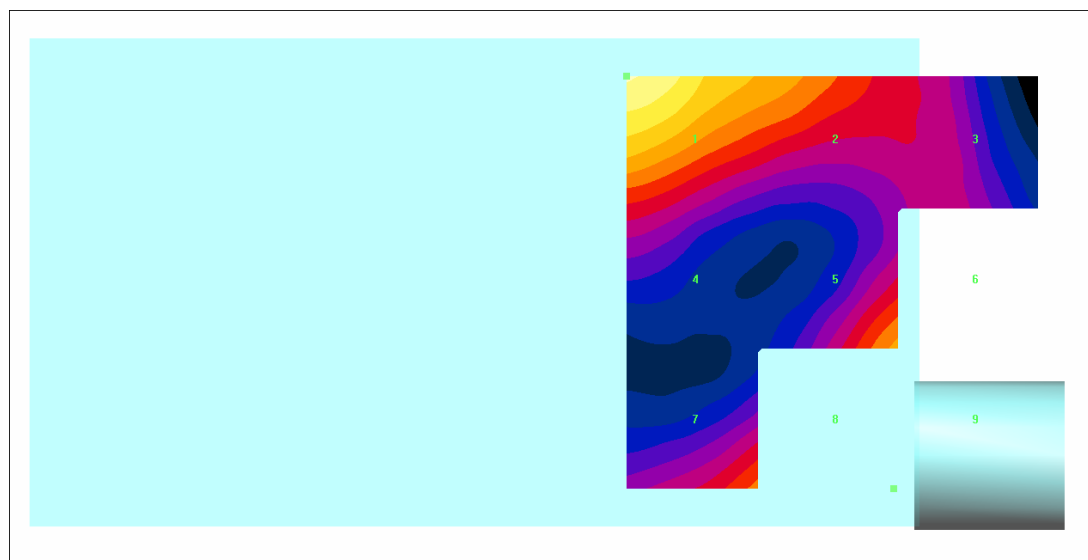
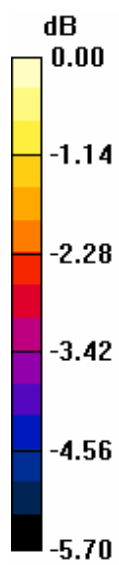
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 53.7 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
53.4	46.3	40.0	53.7	46.6	40.2
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
40.0	45.4	47.1	40.2	45.7	47.4
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
43.5	55.5	55.4	43.8	55.7	55.7

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 55.5V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

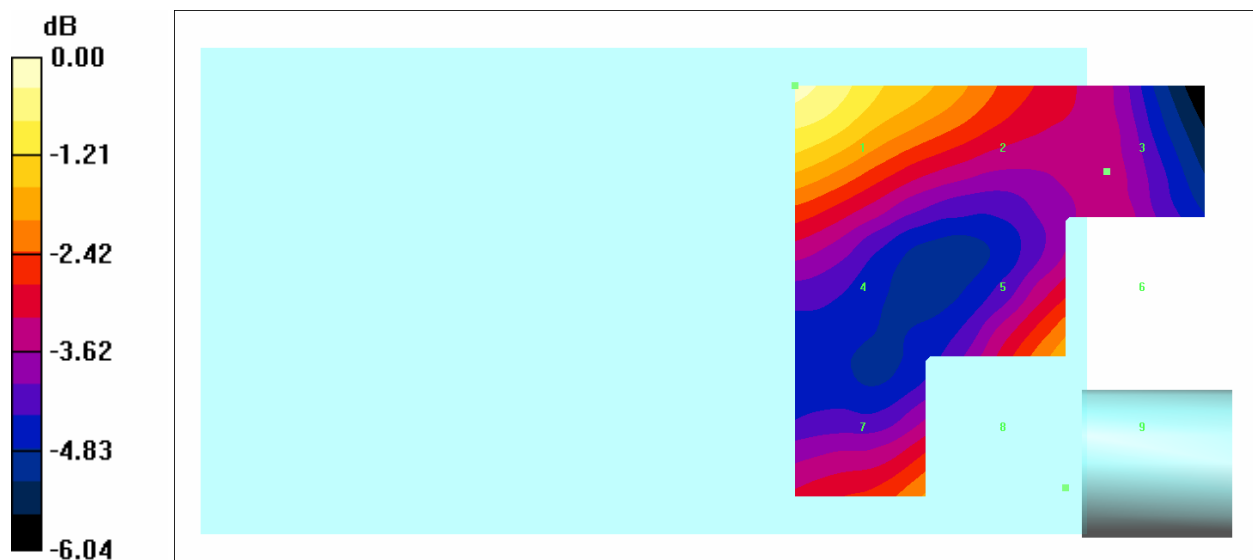
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 52.9 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
52.6	45.1	37.7	52.9	45.3	37.9
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
39.3	44.3	46.0	39.5	44.6	46.2
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
43.2	54.0	54.0	43.4	54.3	54.3

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 54.0V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

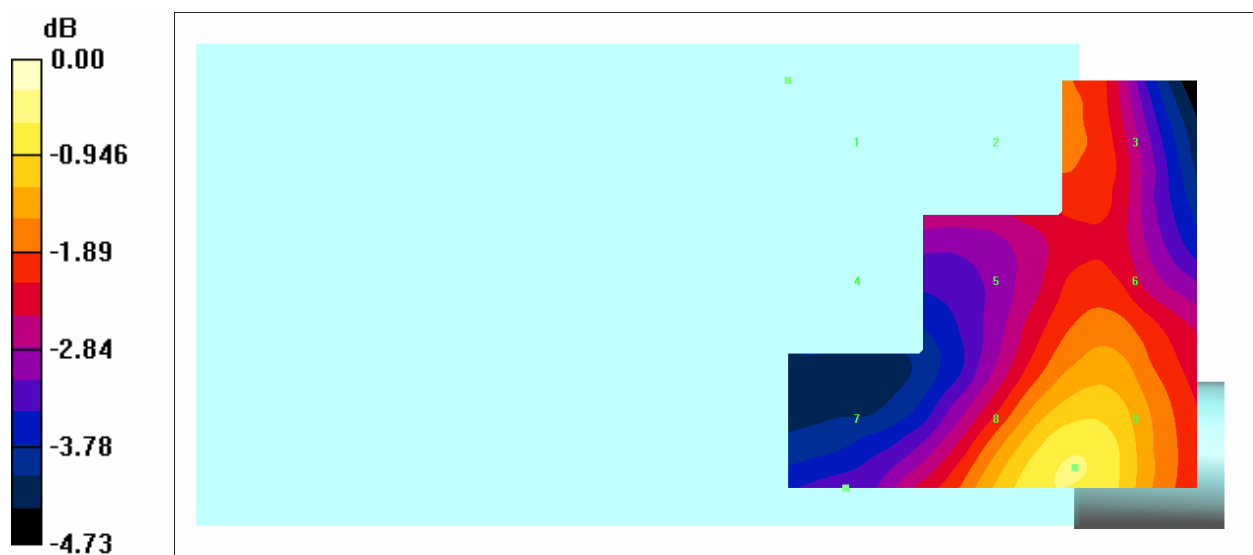
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

**E Scan - ER probe tip 10mm above Device -Low with co-location/Hearing Aid
Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 55.8 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)**

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
59.5	53.5	49.0	59.8	53.7	49.3
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
49.2	48.0	49.8	49.4	48.3	50.1
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
44.9	55.4	55.5	45.1	55.7	55.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 59.5V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz; Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

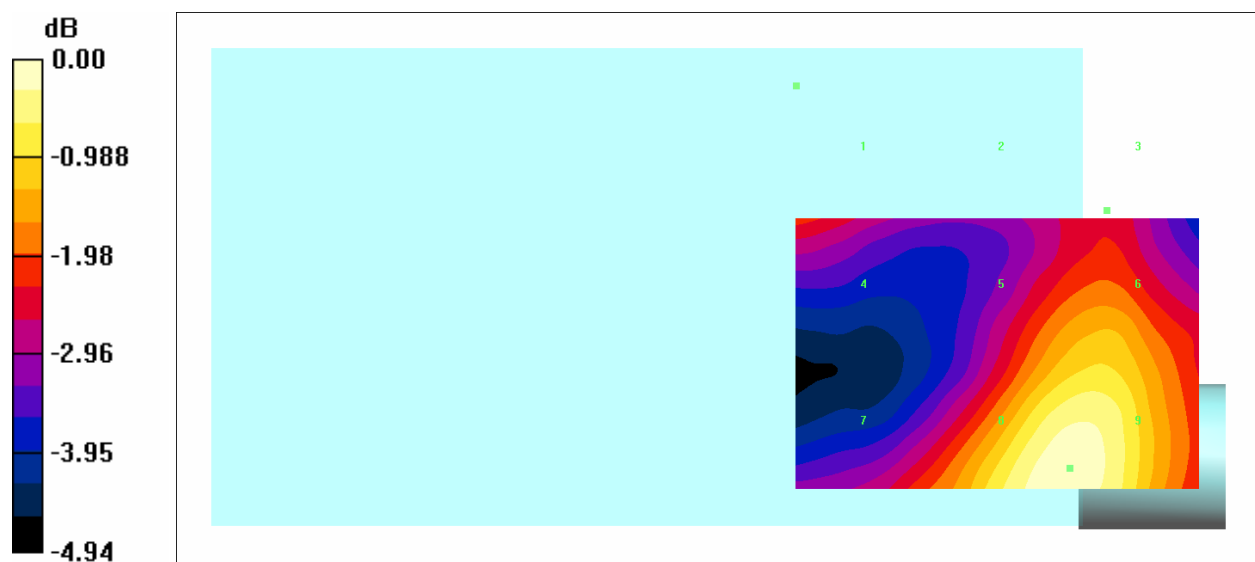
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid with co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 56.1 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 56.3	Grid 2 50.2	Grid 3 44.7	Grid 1 56.6	Grid 2 50.5	Grid 3 44.9
Grid 4 44.0	Grid 5 48.0	Grid 6 49.6	Grid 4 44.2	Grid 5 48.3	Grid 6 49.8
Grid 7 44.5	Grid 8 55.7	Grid 9 55.8	Grid 7 44.7	Grid 8 56.0	Grid 9 56.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 56.3V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

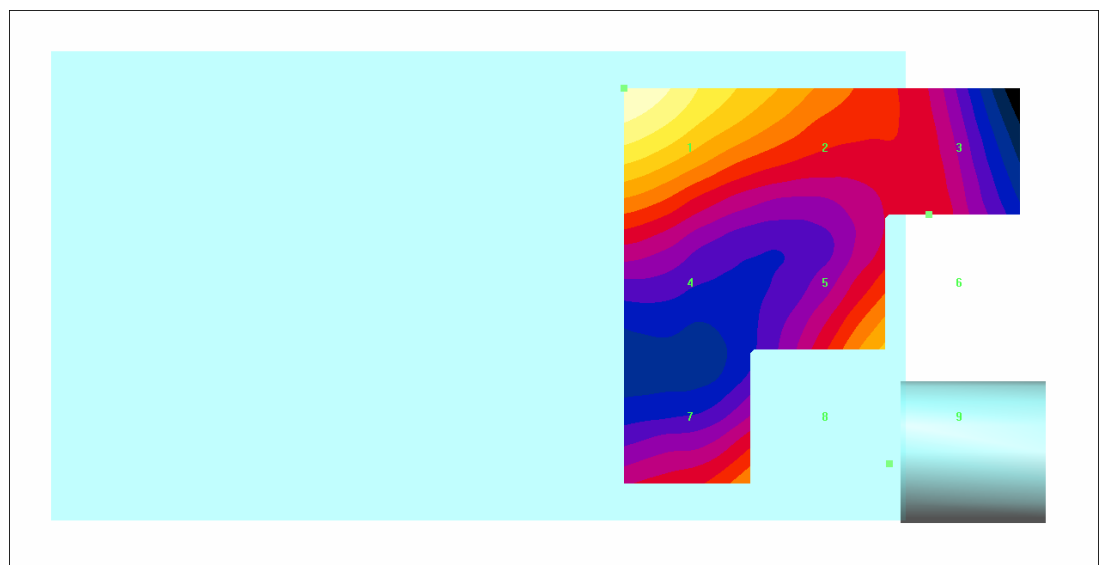
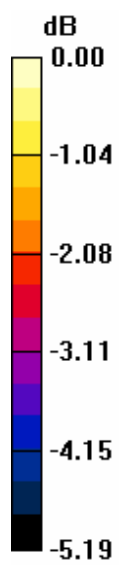
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

**E Scan - ER probe tip 10mm above Device -High with co-location/Hearing Aid
Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 54.8 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)**

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
54.5	47.5	41.7	54.8	47.8	41.9
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
42.4	46.9	48.1	42.7	47.2	48.4
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
44.5	54.5	54.5	44.8	54.8	54.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 54.5V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz;Duty Cycle: 1:1.015
Medium parameters used: $\sigma = 0 \text{ mho/m}$, $\epsilon_r = 1$; $\rho = 1000 \text{ kg/m}^3$
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

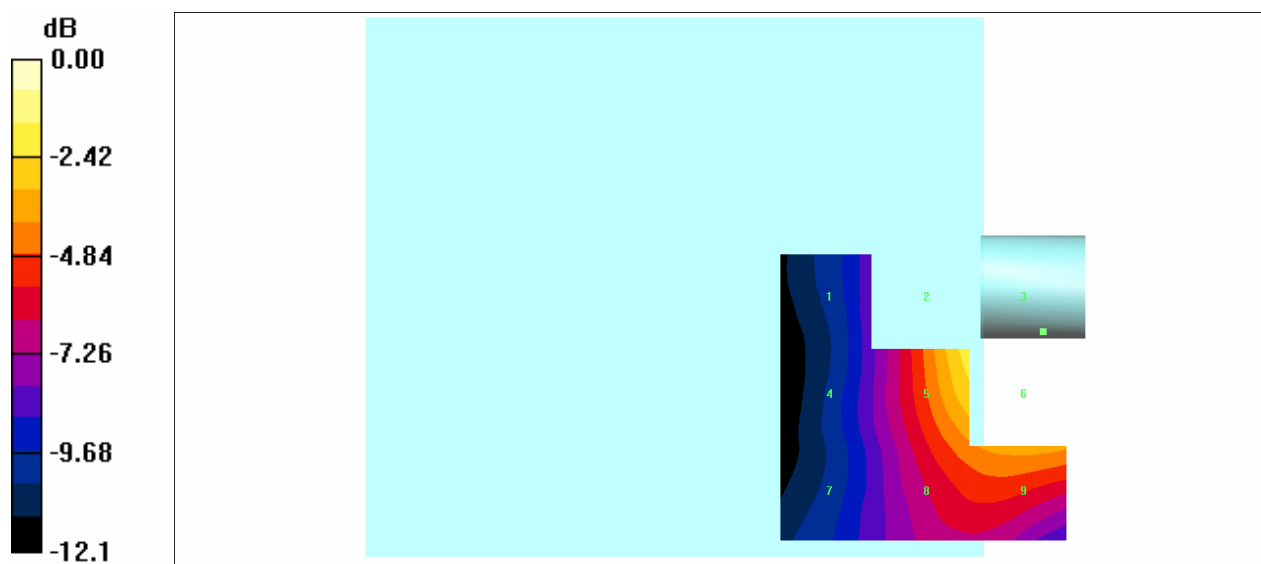
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Low/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 94.9 V/m
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
45.8	96.5	117.0	46.1	97.3	117.9
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
46.1	94.2	115.1	46.4	94.9	116.0
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
44.4	71.9	77.7	44.8	72.5	78.3

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 117.0V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid/Hearing Aid Compatibility Test

(101x101x1): Measurement grid: dx=5mm, dy=5mm

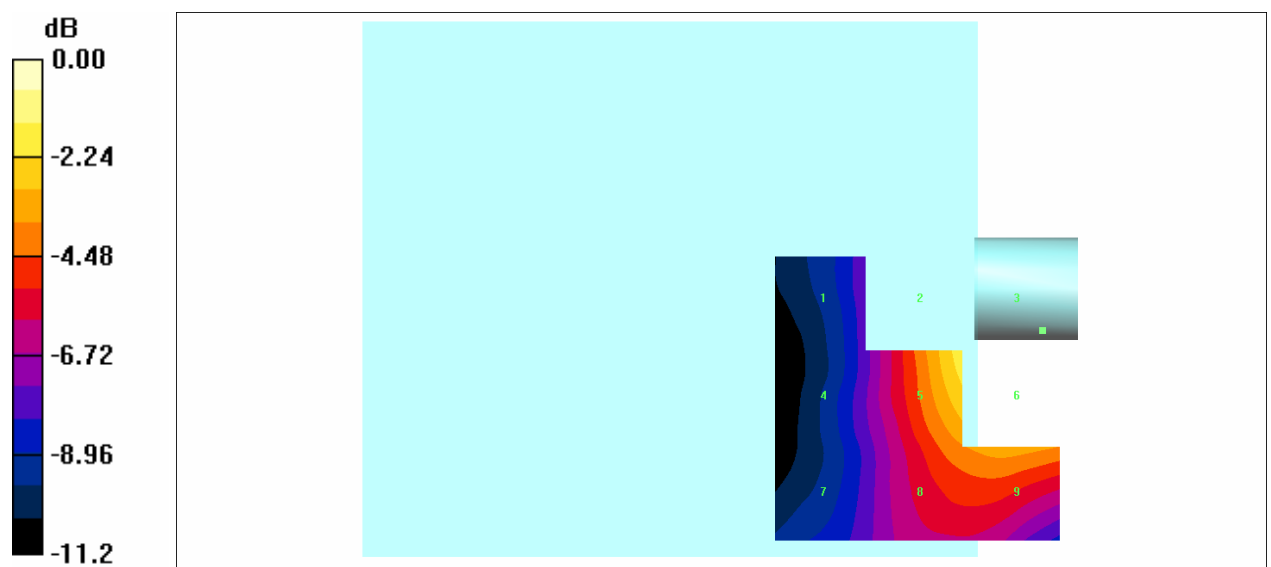
Maximum value of Total field (slot averaged) = 93.3 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 47.3	Grid 2 94.8	Grid 3 112.3	Grid 1 47.7	Grid 2 95.5	Grid 3 113.1
Grid 4 47.4	Grid 5 92.7	Grid 6 110.4	Grid 4 47.7	Grid 5 93.3	Grid 6 111.2
Grid 7 46.3	Grid 8 72.6	Grid 9 77.0	Grid 7 46.7	Grid 8 73.2	Grid 9 77.5

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 112.3V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High/Hearing Aid Compatibility Test

(101x101x1): Measurement grid: dx=5mm, dy=5mm

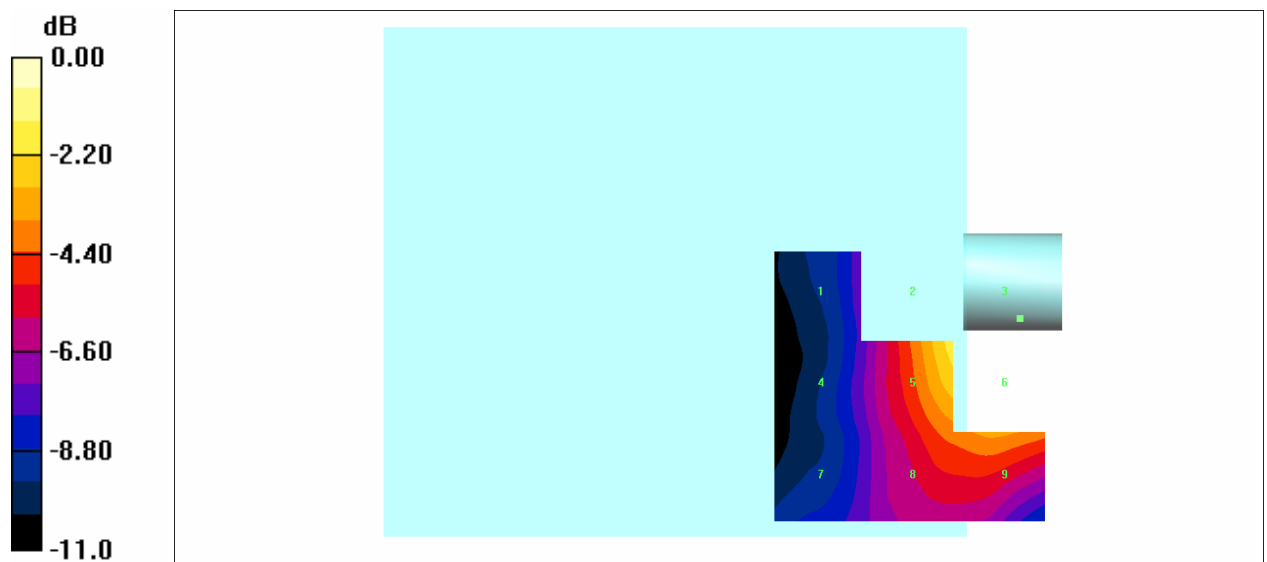
Maximum value of Total field (slot averaged) = 92.1 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
47.0	94.3	111.8	47.4	95.0	112.7
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
47.2	91.4	109.4	47.6	92.1	110.2
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
46.7	70.3	75.3	47.0	70.8	75.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 111.8V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High/Hearing Aid Compatibility Test

(101x101x1): Measurement grid: dx=5mm, dy=5mm

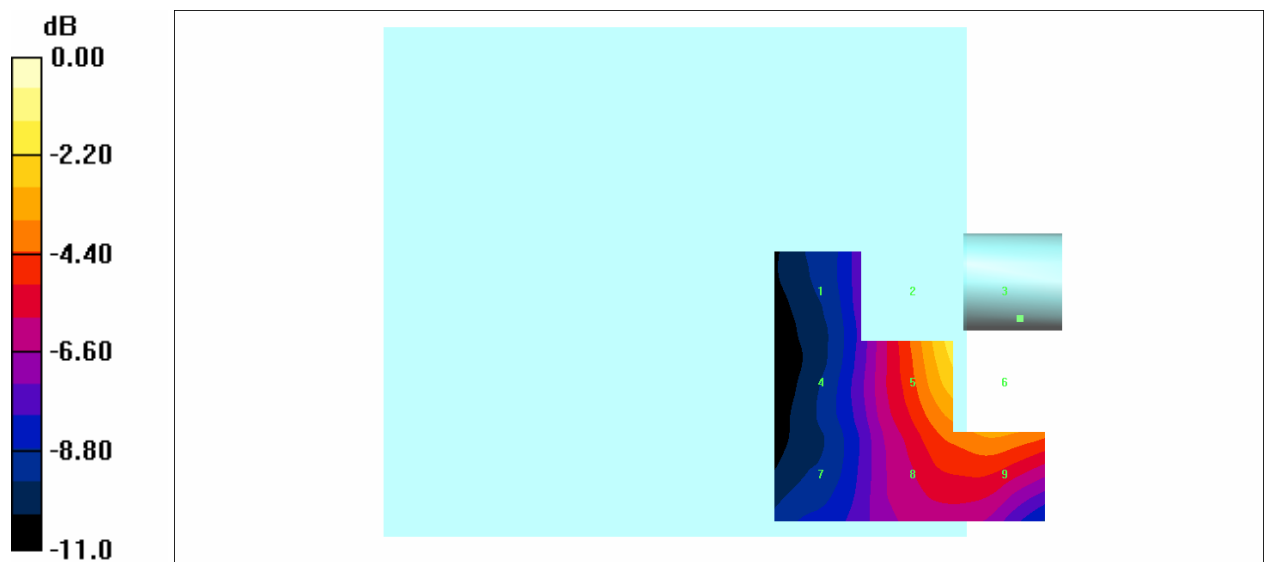
Maximum value of Total field (slot averaged) = 92.1 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
47.0	94.3	111.8	47.4	95.0	112.7
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
47.2	91.4	109.4	47.6	92.1	110.2
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
46.7	70.3	75.3	47.0	70.8	75.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 111.8V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Low with co-location/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

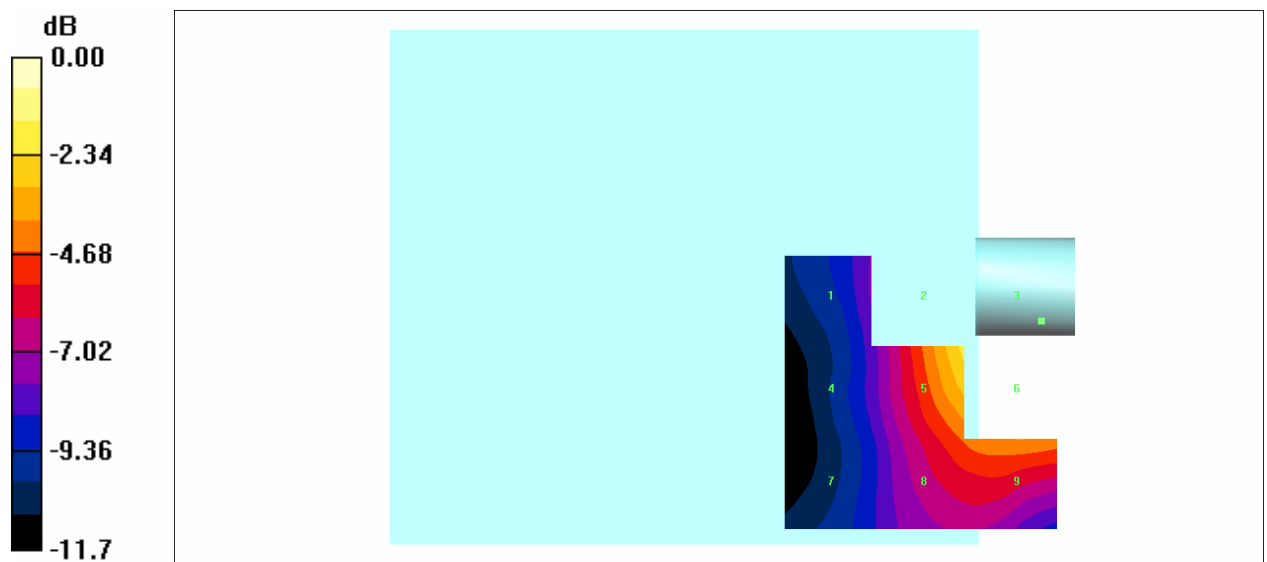
Maximum value of Total field (slot averaged) = 97.0 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
50.5	99.5	120.9	50.8	100.2	121.8
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
47.5	96.2	117.7	47.9	97.0	118.6
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
44.5	72.0	77.6	44.8	72.5	78.2

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid with co-location/Hearing Aid Compatibility

Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

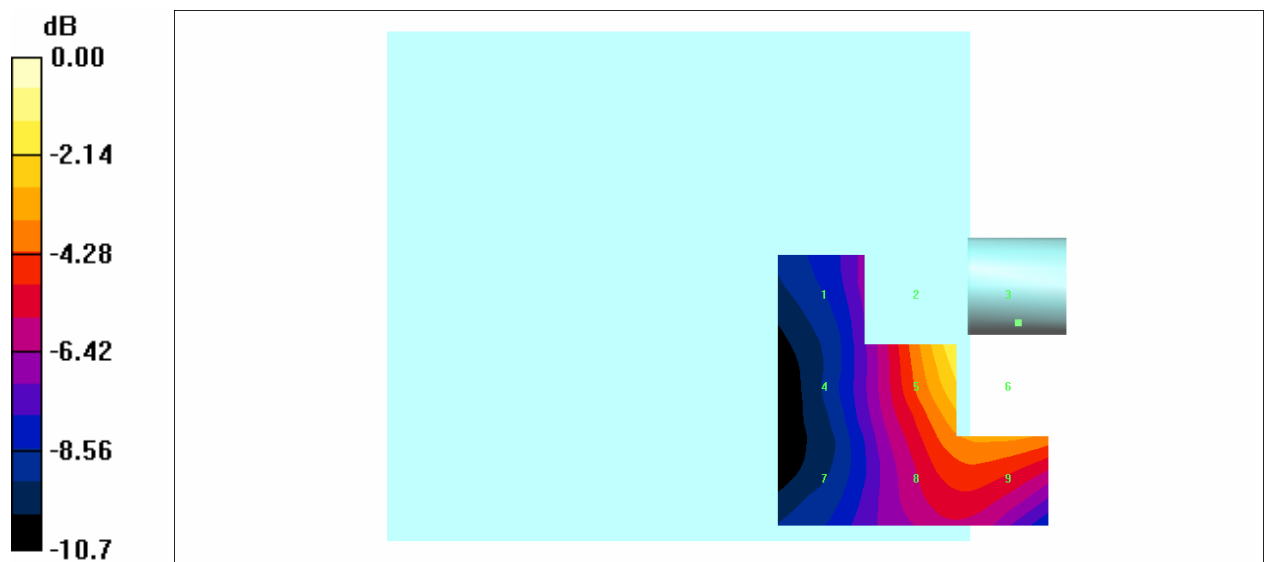
Maximum value of Total field (slot averaged) = 96.4 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
52.0	98.9	113.1	52.3	99.7	113.9
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
49.4	95.7	110.9	49.8	96.4	111.7
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
48.1	74.4	77.3	48.4	74.9	77.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 113.1V/m

Date/Time: 2005/7/28 11:15:30 PMDate/Time: 2005/7/28 11:19:45PMDate/Time: 2005/7/28 11:18:41 PM

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz;Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASYS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)Sensor-Surface: 0mm (Fix Surface)Sensor-Surface: 4mm (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASYS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High with co-location/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 98.4 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
54.6	100.1	114.3	55.0	100.9	115.2
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
52.4	97.7	112.0	52.8	98.4	112.9
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
51.0	74.9	78.9	51.3	75.5	79.5

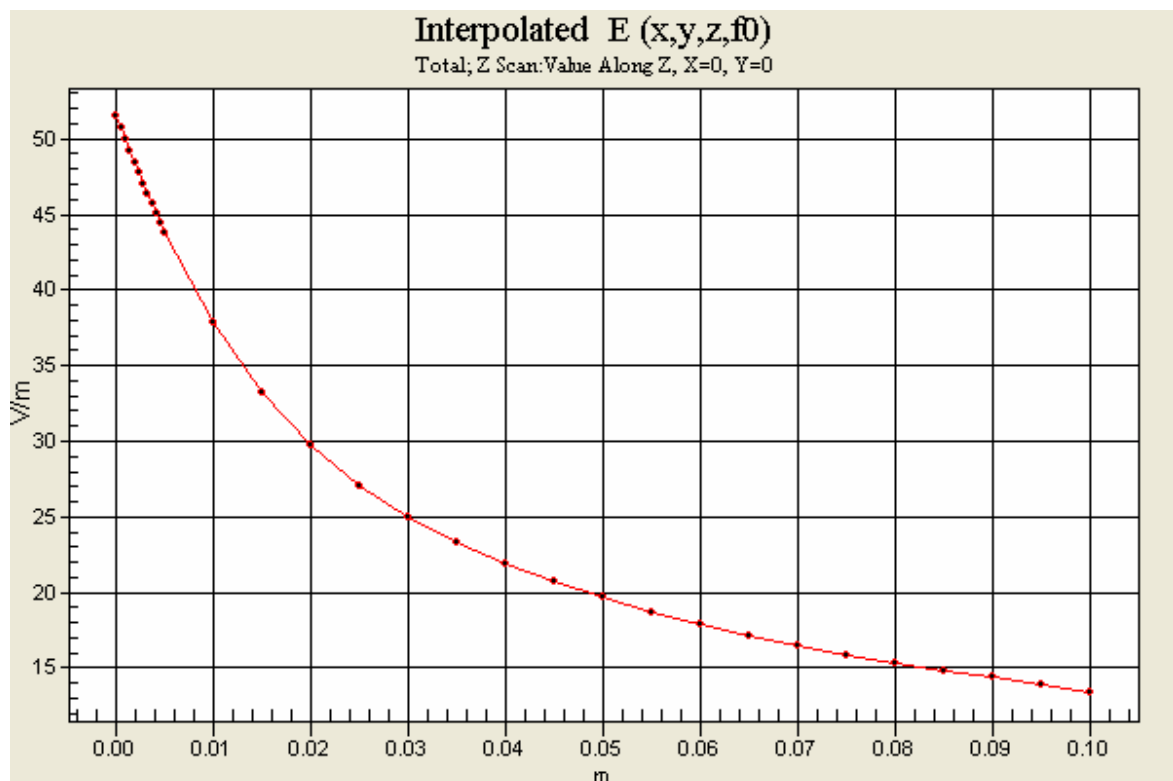
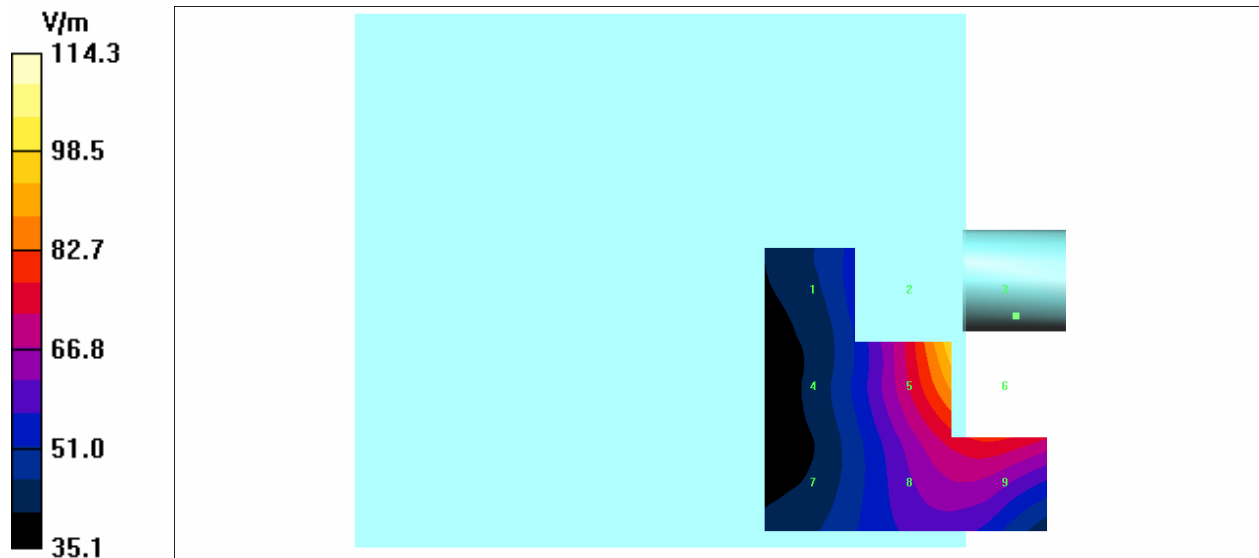
Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15

E Scan - ER probe tip 10mm above Device -High with co-location/Z Scan (1x1x31):

Measurement grid: $dx=20\text{mm}$, $dy=20\text{mm}$, $dz=5\text{mm}$

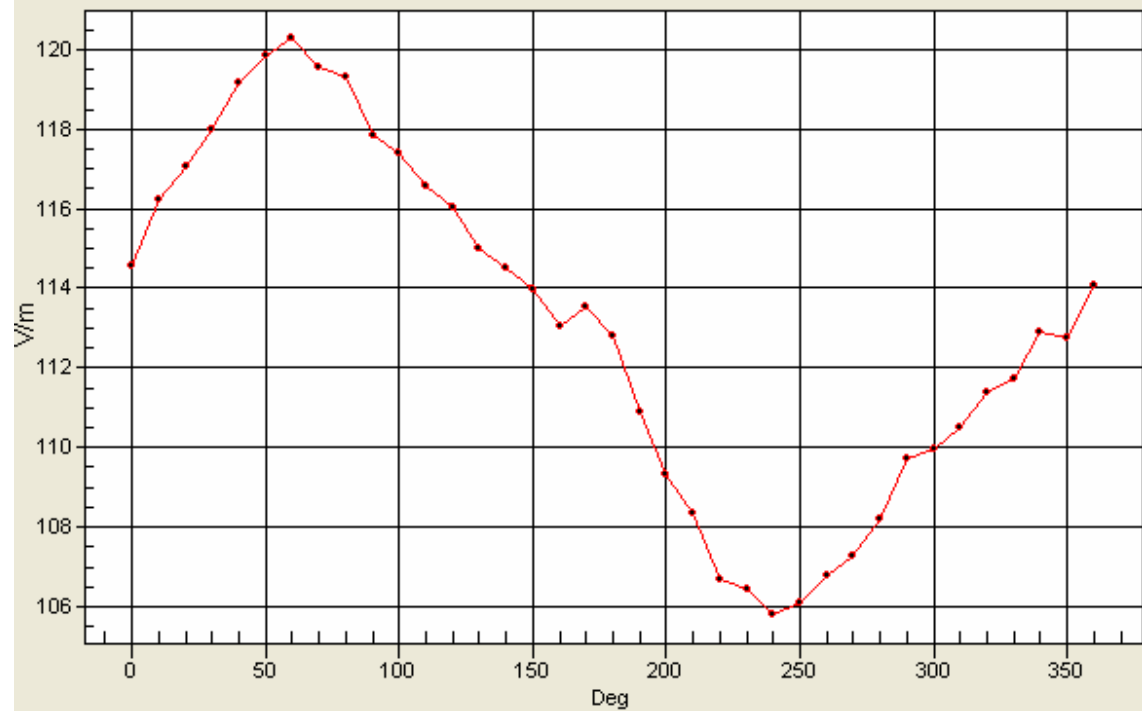
Maximum value of Total (interpolated) = 51.5 V/m

E Scan - ER probe tip 10mm above Device -High with co-location/Rotation (1D): 37 rotation steps; E-Field Max Isotropy Error = $\pm 0.57\text{ dB}$;



E(roll)

E_tot;; E-Field Max Isotropy Error = 7.57 dB;



Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA835(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz;Duty Cycle: 1:1.015
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

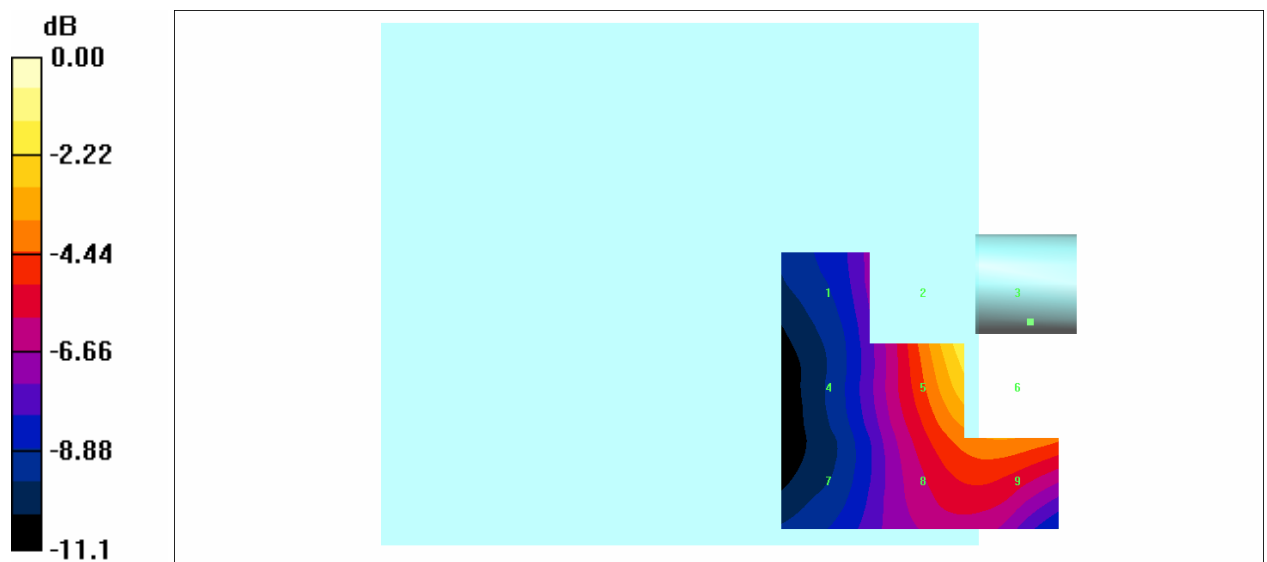
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High with co-location and Backlight on/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 94.1 V/m
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
49.9	96.4	112.8	50.2	97.1	113.6
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
47.3	93.4	109.7	47.7	94.1	110.6
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
46.2	71.1	74.4	46.5	71.6	74.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 112.8V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

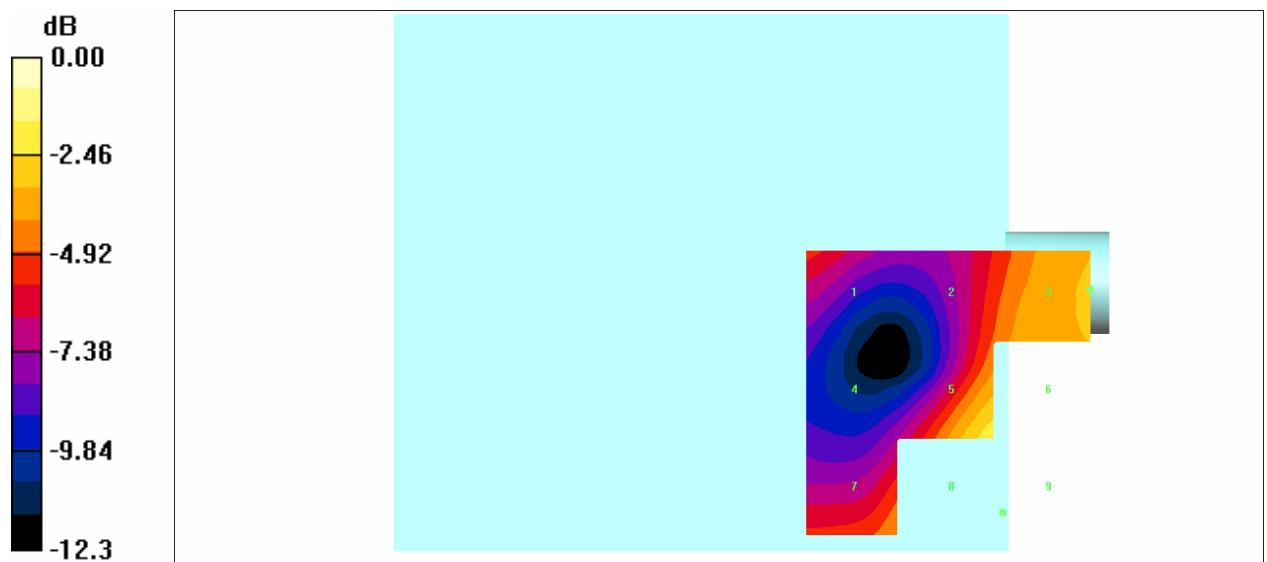
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Low/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 34.5 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
23.2	24.6	29.7	23.3	24.7	29.8
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
18.2	34.3	35.5	18.3	34.5	35.6
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
26.5	42.5	42.6	26.7	42.7	42.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 42.6V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

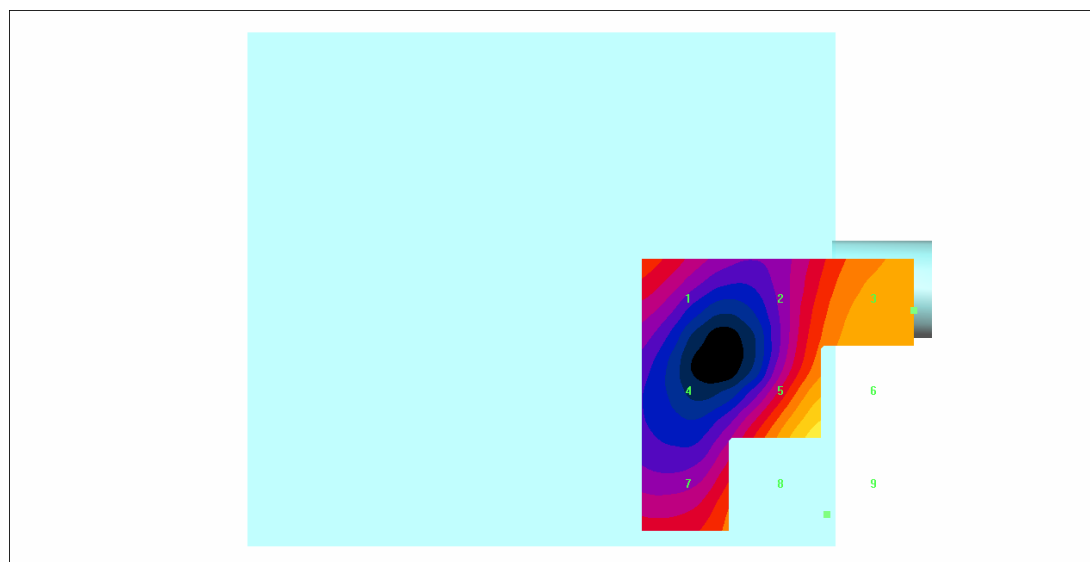
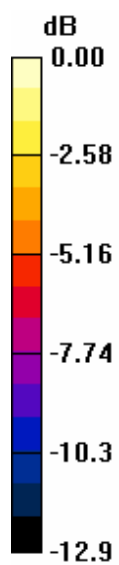
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 35.9 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
24.0	25.1	28.8	24.1	25.3	29.0
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
18.1	35.7	36.7	18.2	35.9	36.9
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
25.7	44.6	44.7	25.8	44.8	44.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 44.7V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

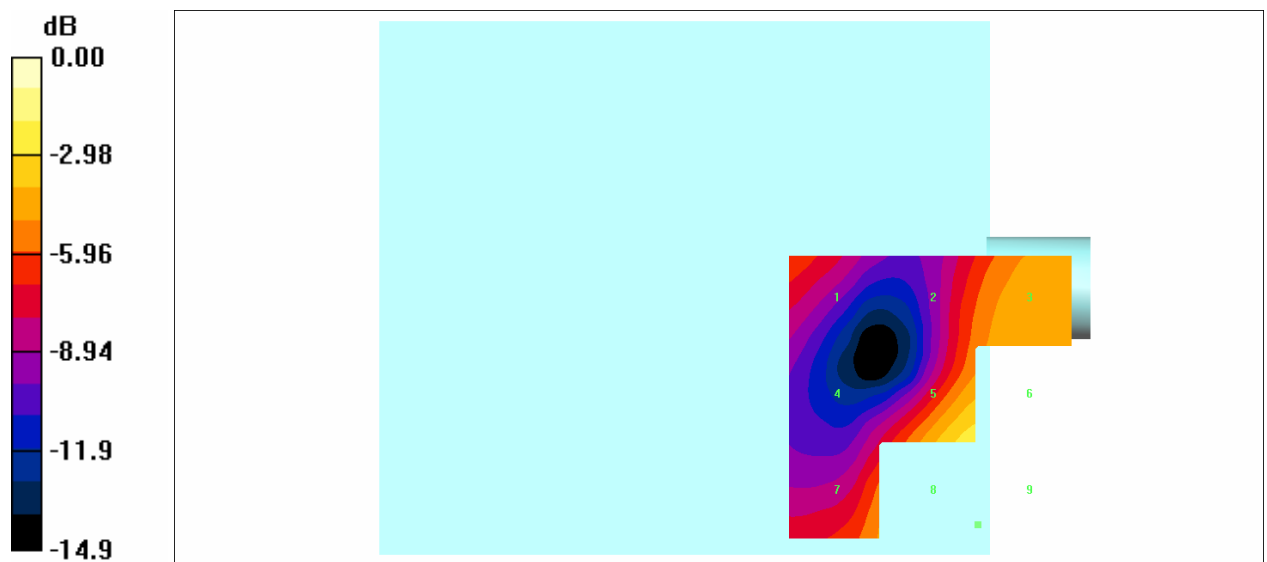
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -High/Hearing Aid Compatibility Test
(101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 36.8 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
23.9	25.1	29.1	24.0	25.2	29.3
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
19.1	36.6	37.5	19.2	36.8	37.7
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
27.2	47.3	47.4	27.3	47.6	47.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 47.4V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz; Duty Cycle: 1:1.01

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Low with co-location/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

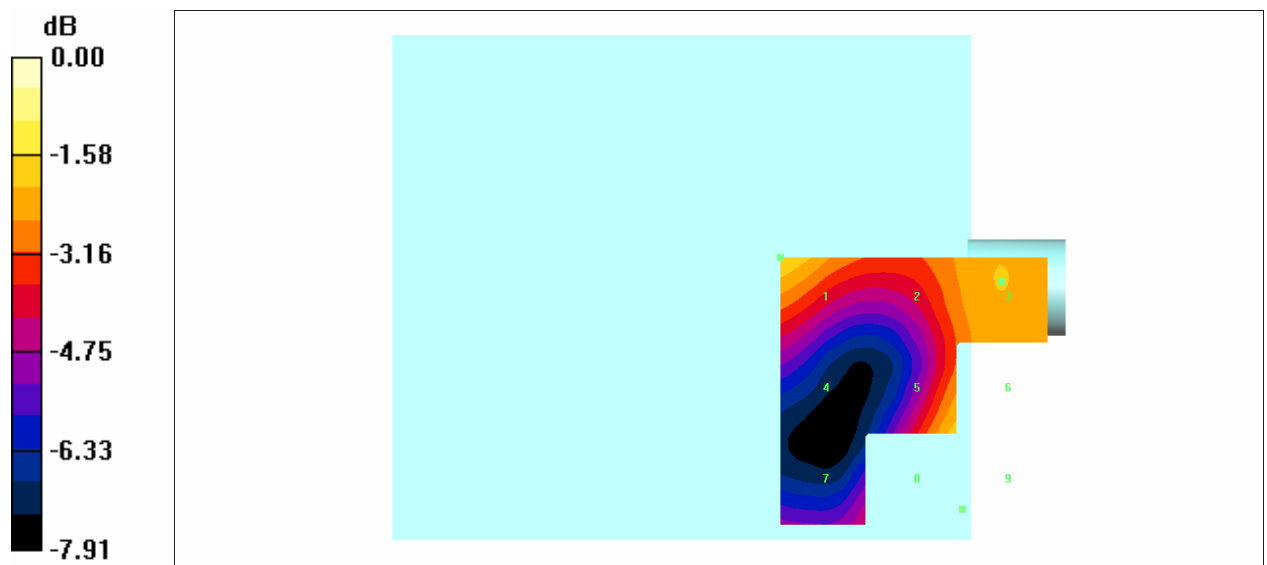
Maximum value of Total field (slot averaged) = 36.7 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 36.5	Grid 2 32.5	Grid 3 34.3	Grid 1 36.7	Grid 2 32.7	Grid 3 34.5
Grid 4 26.0	Grid 5 35.5	Grid 6 36.6	Grid 4 26.1	Grid 5 35.7	Grid 6 36.8
Grid 7 26.9	Grid 8 43.4	Grid 9 43.6	Grid 7 27.0	Grid 8 43.7	Grid 9 43.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 43.6V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

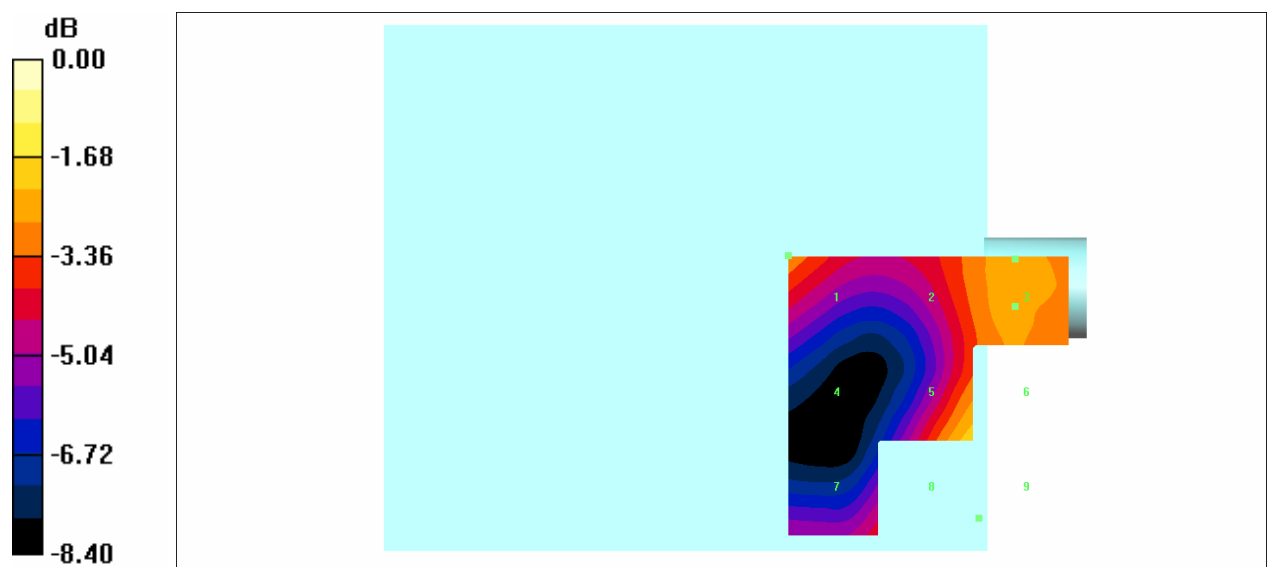
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - ER probe tip 10mm above Device -Mid with co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 36.7 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
32.2	31.6	33.5	32.4	31.8	33.7
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
22.7	36.5	37.6	22.9	36.7	37.8
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
28.1	44.8	44.9	28.3	45.0	45.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 44.9V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_E_SCAN_CDMA1900(Open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz;Duty Cycle: 1:1.01
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³
Phantom section: E Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

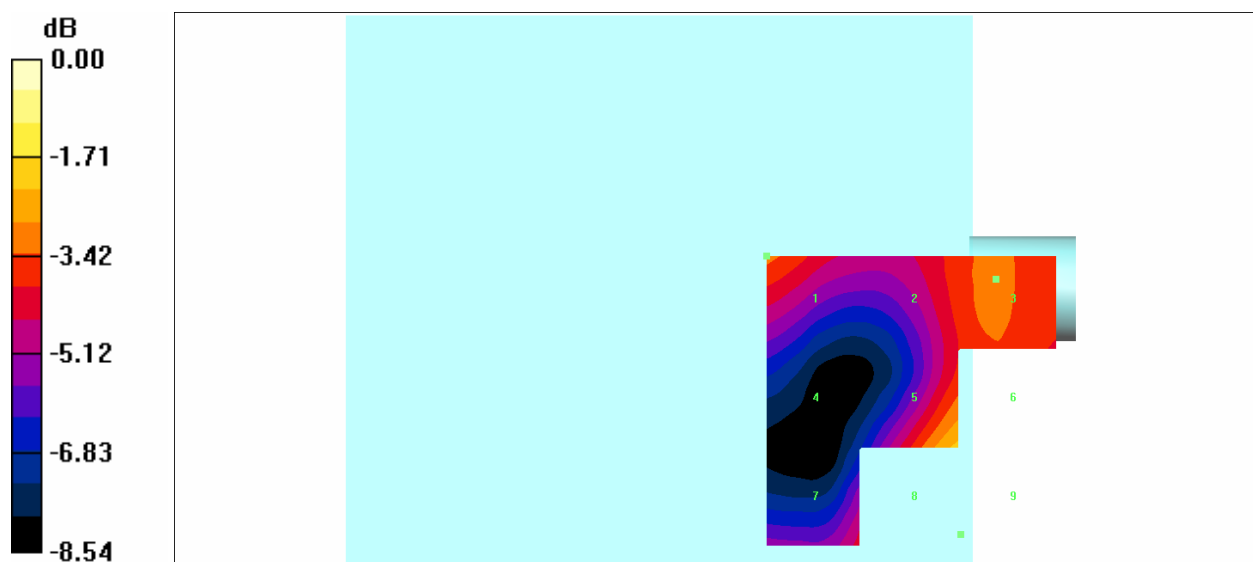
- Probe: ER3DV6 - SN2345; ConvF(1, 1, 1); Calibrated: 2005/6/3
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

**E Scan - ER probe tip 10mm above Device -High with co-location/Hearing Aid
Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 36.6 V/m
Hearing Aid Near-Field Category: M4 (AWF 0 dB)**

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
32.1	30.4	31.9	32.2	30.5	32.1
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
23.3	36.4	37.2	23.4	36.6	37.4
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
28.3	46.2	46.3	28.4	46.5	46.5

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 46.3V/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.165 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.145	0.144	0.136
Grid 4	Grid 5	Grid 6
0.159	0.164	0.162
Grid 7	Grid 8	Grid 9
0.162	0.168	0.167

Grid 1	Grid 2	Grid 3
0.146	0.145	0.137
Grid 4	Grid 5	Grid 6
0.160	0.165	0.163
Grid 7	Grid 8	Grid 9
0.163	0.169	0.168

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.168A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

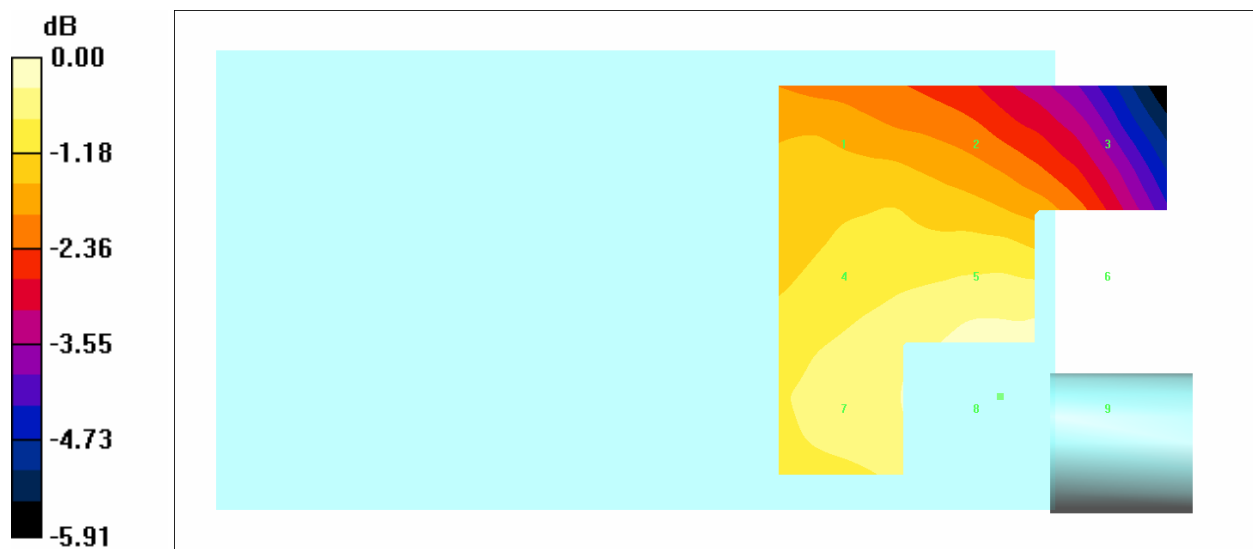
Maximum value of Total field (slot averaged) = 0.166 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.147	Grid 2 0.146	Grid 3 0.137	Grid 1 0.148	Grid 2 0.147	Grid 3 0.139
Grid 4 0.158	Grid 5 0.165	Grid 6 0.165	Grid 4 0.159	Grid 5 0.166	Grid 6 0.166
Grid 7 0.161	Grid 8 0.168	Grid 9 0.168	Grid 7 0.162	Grid 8 0.169	Grid 9 0.169

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.168A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-High/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

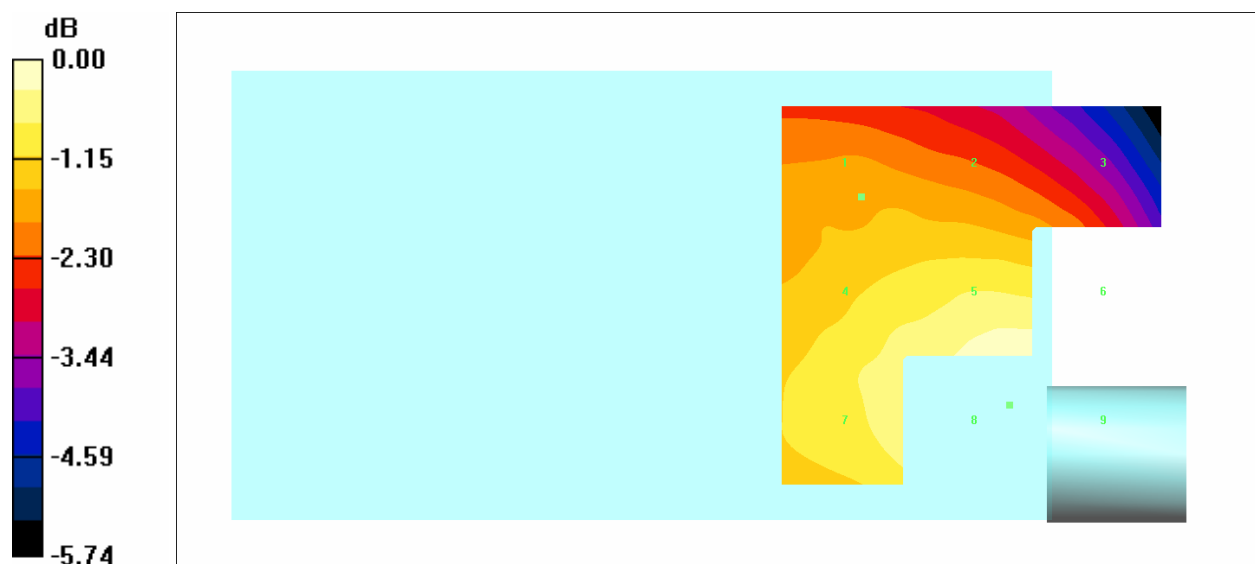
Maximum value of Total field (slot averaged) = 0.163 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.141	Grid 2 0.141	Grid 3 0.135	Grid 1 0.142	Grid 2 0.142	Grid 3 0.136
Grid 4 0.153	Grid 5 0.162	Grid 6 0.162	Grid 4 0.154	Grid 5 0.163	Grid 6 0.163
Grid 7 0.155	Grid 8 0.165	Grid 9 0.165	Grid 7 0.156	Grid 8 0.167	Grid 9 0.166

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.165A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz;Duty Cycle: 1:1.015
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³
Phantom section: H Device Section
Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

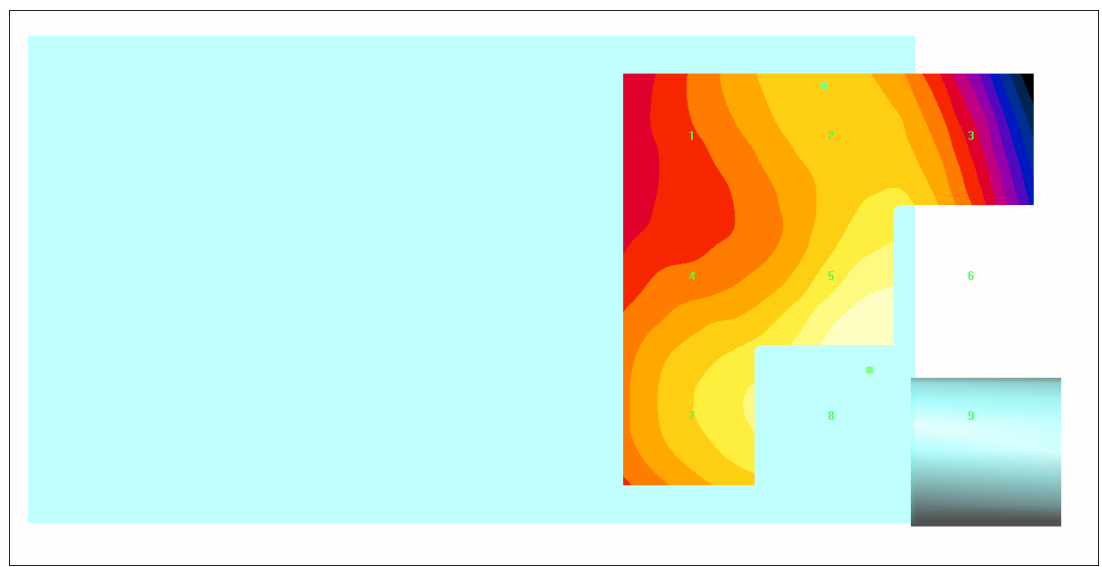
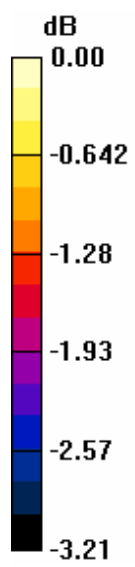
- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.216 A/m
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
0.195	0.201	0.201	0.196	0.203	0.203
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
0.201	0.215	0.214	0.202	0.216	0.216
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
0.206	0.215	0.215	0.207	0.217	0.216

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.215A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz;Duty Cycle: 1:1.015
Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³
Phantom section: H Device Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

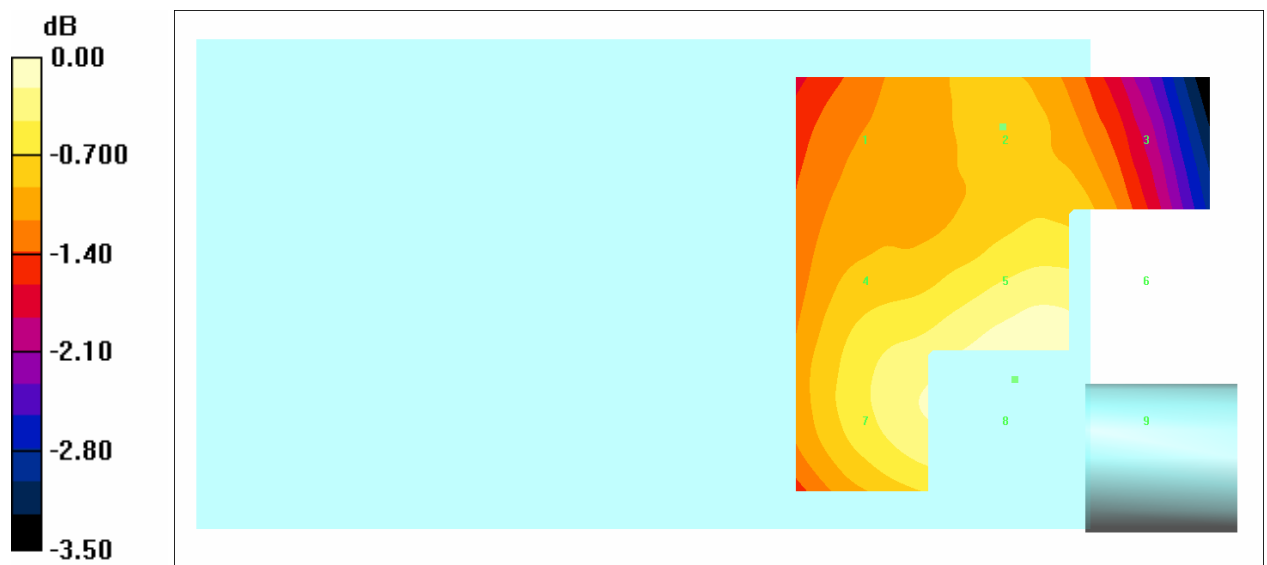
- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.218 A/m
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
0.194	0.201	0.199	0.196	0.202	0.201
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
0.209	0.217	0.215	0.211	0.218	0.217
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
0.213	0.218	0.216	0.215	0.219	0.217

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.218A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(Close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

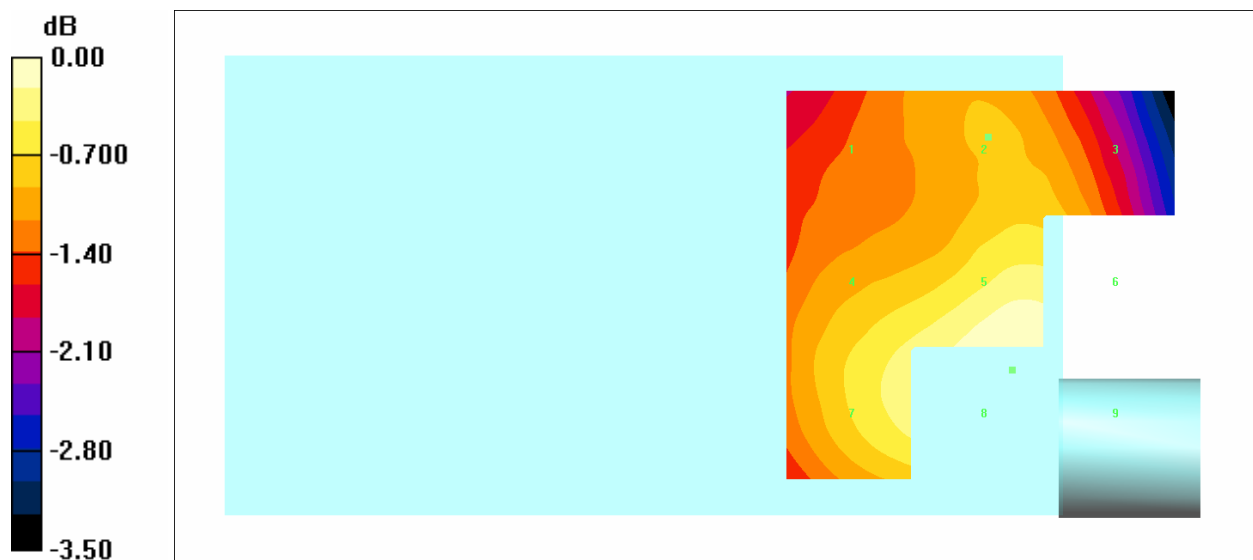
H Scan - H3DV6 probe center 10mm above Device Reference-High with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.214 A/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.187	Grid 2 0.196	Grid 3 0.195	Grid 1 0.189	Grid 2 0.197	Grid 3 0.196
Grid 4 0.203	Grid 5 0.213	Grid 6 0.211	Grid 4 0.205	Grid 5 0.214	Grid 6 0.213
Grid 7 0.205	Grid 8 0.213	Grid 9 0.212	Grid 7 0.207	Grid 8 0.215	Grid 9 0.214

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.213A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.176 A/m

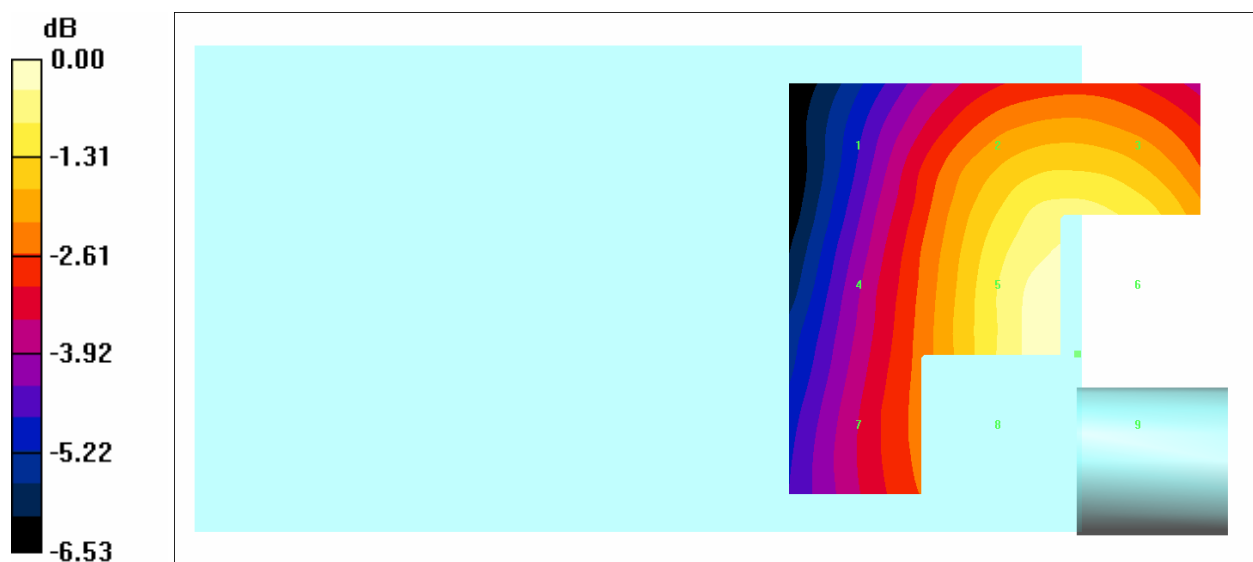
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.127	0.162	0.162
Grid 4	Grid 5	Grid 6
0.132	0.174	0.175
Grid 7	Grid 8	Grid 9
0.133	0.174	0.175

Grid 1	Grid 2	Grid 3
0.128	0.163	0.164
Grid 4	Grid 5	Grid 6
0.134	0.176	0.177
Grid 7	Grid 8	Grid 9
0.134	0.176	0.177

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.175A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

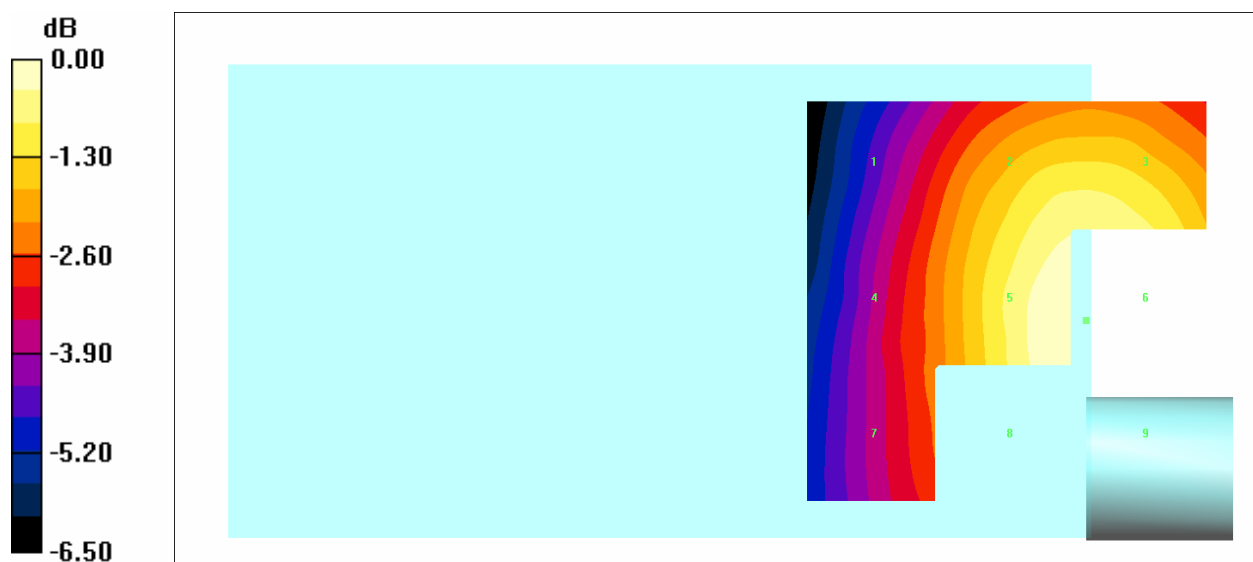
Maximum value of Total field (slot averaged) = 0.156 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.115	Grid 2 0.147	Grid 3 0.147	Grid 1 0.116	Grid 2 0.148	Grid 3 0.148
Grid 4 0.118	Grid 5 0.155	Grid 6 0.155	Grid 4 0.119	Grid 5 0.156	Grid 6 0.156
Grid 7 0.118	Grid 8 0.153	Grid 9 0.153	Grid 7 0.119	Grid 8 0.155	Grid 9 0.155

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.155A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-High/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

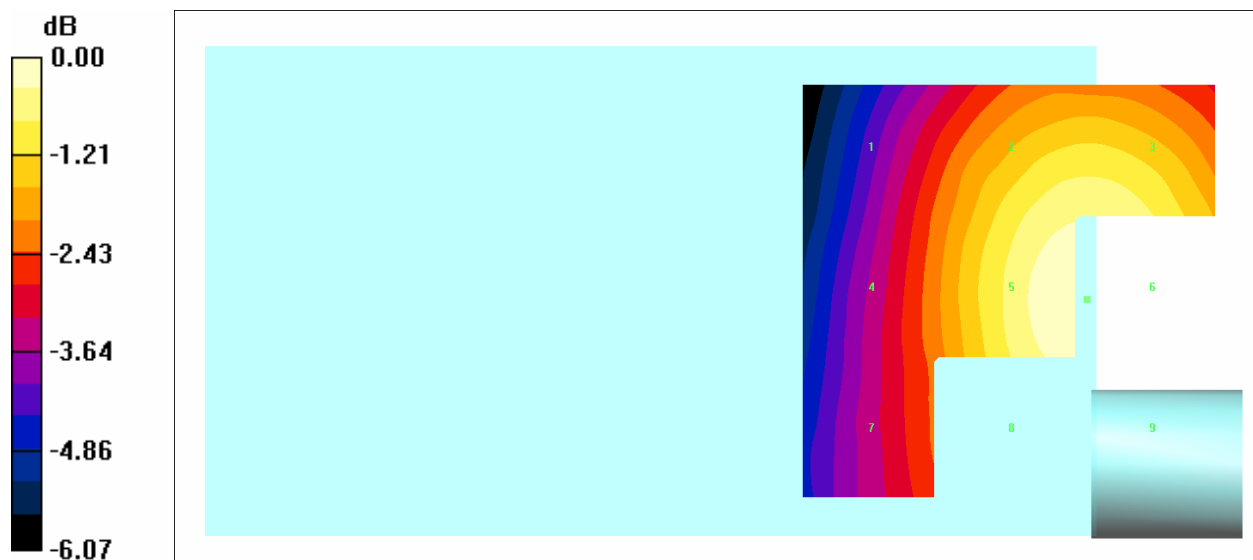
Maximum value of Total field (slot averaged) = 0.155 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.118	Grid 2 0.146	Grid 3 0.147	Grid 1 0.119	Grid 2 0.148	Grid 3 0.148
Grid 4 0.120	Grid 5 0.154	Grid 6 0.154	Grid 4 0.121	Grid 5 0.155	Grid 6 0.156
Grid 7 0.119	Grid 8 0.150	Grid 9 0.150	Grid 7 0.120	Grid 8 0.151	Grid 9 0.152

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.154A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.179 A/m

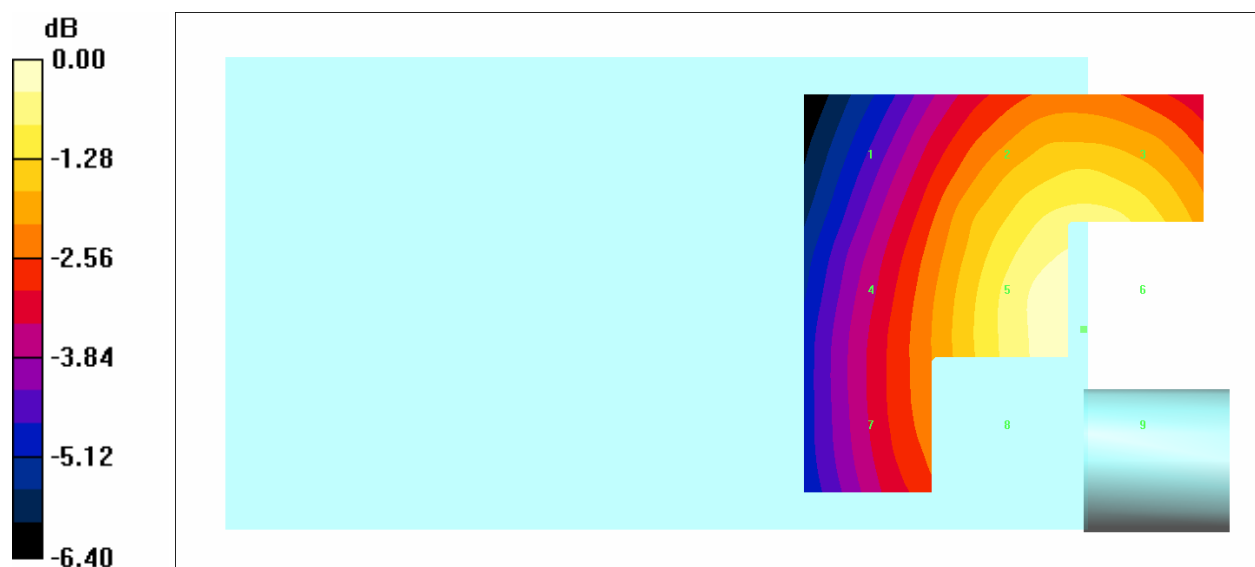
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.133	0.166	0.166
Grid 4	Grid 5	Grid 6
0.140	0.178	0.179
Grid 7	Grid 8	Grid 9
0.140	0.176	0.177

Grid 1	Grid 2	Grid 3
0.134	0.167	0.167
Grid 4	Grid 5	Grid 6
0.142	0.179	0.180
Grid 7	Grid 8	Grid 9
0.141	0.178	0.178

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.179A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

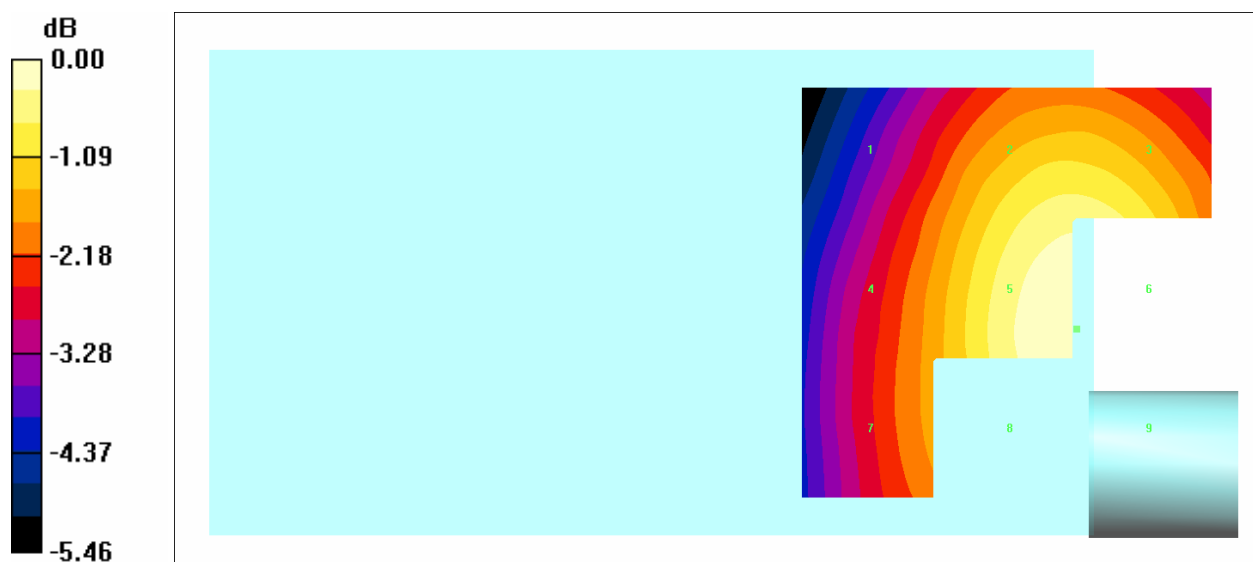
Maximum value of Total field (slot averaged) = **0.168 A/m**

Hearing Aid Near-Field Category: **M4 (AWF 0 dB)**

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.132	Grid 2 0.158	Grid 3 0.158	Grid 1 0.134	Grid 2 0.159	Grid 3 0.159
Grid 4 0.139	Grid 5 0.167	Grid 6 0.167	Grid 4 0.140	Grid 5 0.168	Grid 6 0.168
Grid 7 0.139	Grid 8 0.166	Grid 9 0.166	Grid 7 0.140	Grid 8 0.167	Grid 9 0.167

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.167A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(close)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

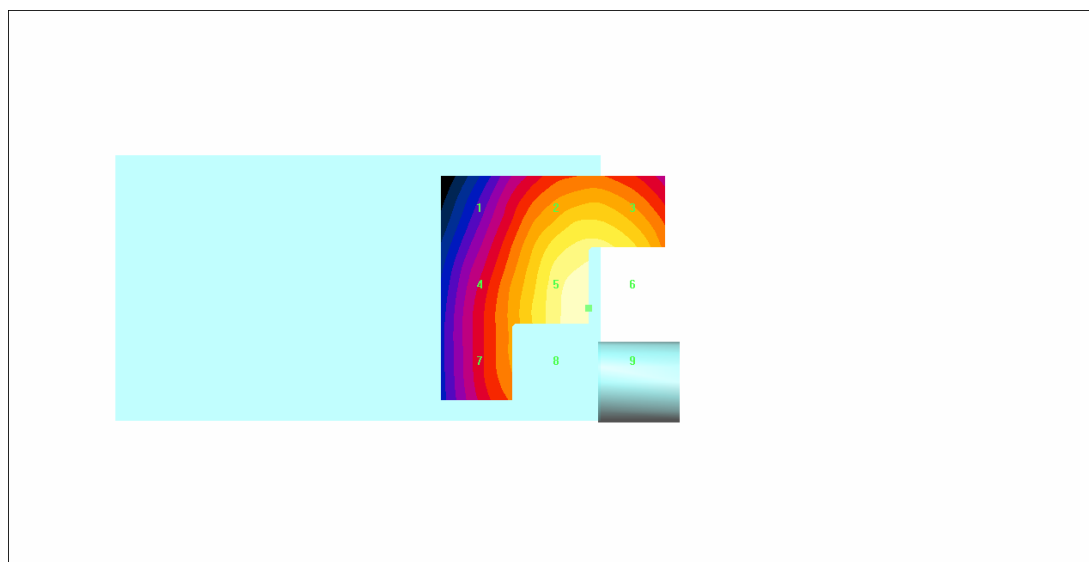
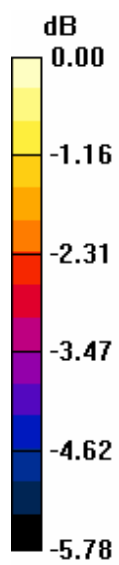
H Scan - H3DV6 probe center 10mm above Device Reference-High with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.169 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.130	Grid 2 0.157	Grid 3 0.157	Grid 1 0.131	Grid 2 0.158	Grid 3 0.158
Grid 4 0.137	Grid 5 0.168	Grid 6 0.168	Grid 4 0.139	Grid 5 0.169	Grid 6 0.169
Grid 7 0.137	Grid 8 0.167	Grid 9 0.167	Grid 7 0.138	Grid 8 0.169	Grid 9 0.169

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.168A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.159 A/m

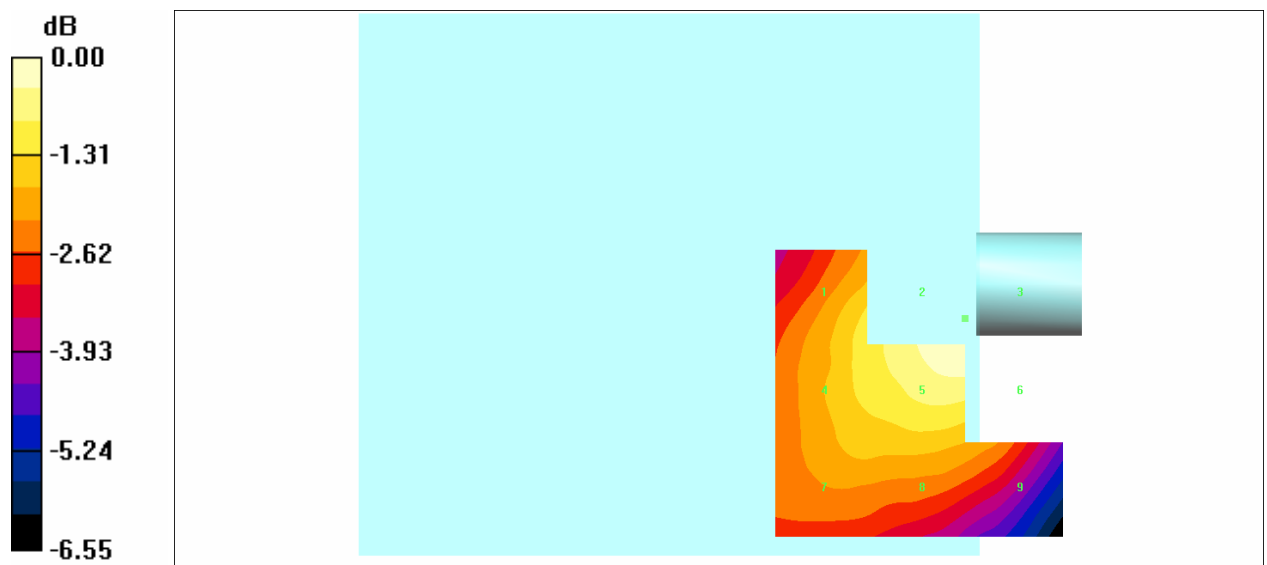
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.141	0.159	0.159
Grid 4	Grid 5	Grid 6
0.141	0.158	0.158
Grid 7	Grid 8	Grid 9
0.133	0.134	0.130

Grid 1	Grid 2	Grid 3
0.142	0.160	0.160
Grid 4	Grid 5	Grid 6
0.142	0.159	0.159
Grid 7	Grid 8	Grid 9
0.134	0.135	0.131

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.159A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

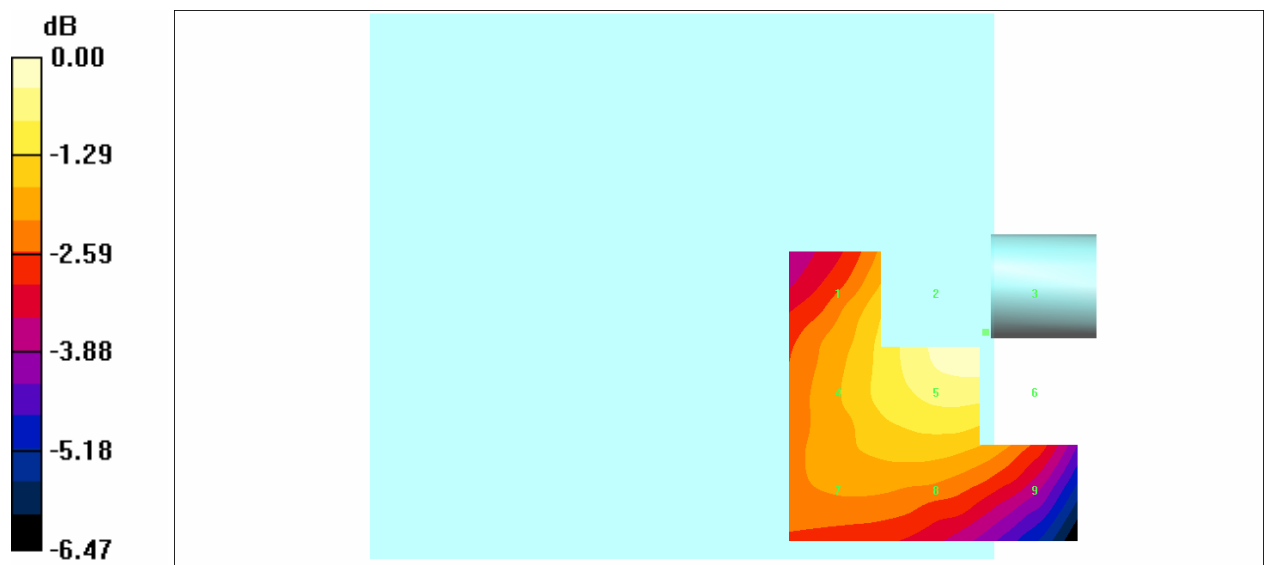
Maximum value of Total field (slot averaged) = 0.160 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.141	Grid 2 0.160	Grid 3 0.161	Grid 1 0.142	Grid 2 0.161	Grid 3 0.162
Grid 4 0.141	Grid 5 0.159	Grid 6 0.159	Grid 4 0.142	Grid 5 0.160	Grid 6 0.160
Grid 7 0.134	Grid 8 0.136	Grid 9 0.132	Grid 7 0.135	Grid 8 0.137	Grid 9 0.133

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.161A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-High/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.154 A/m

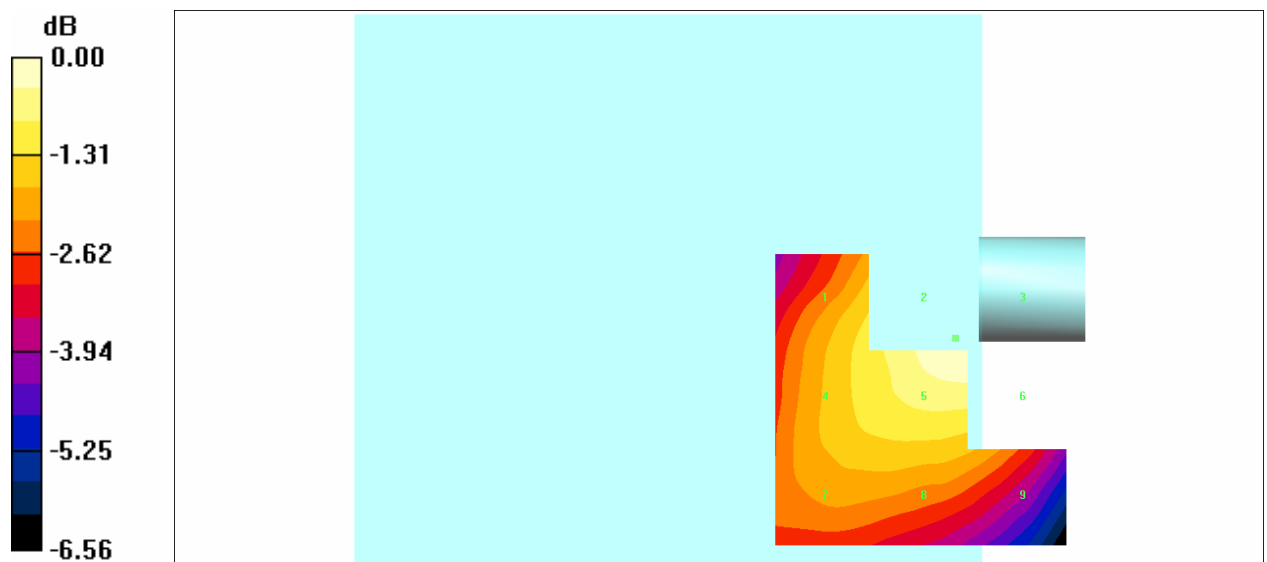
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.136	0.154	0.153
Grid 4	Grid 5	Grid 6
0.136	0.153	0.152
Grid 7	Grid 8	Grid 9
0.130	0.131	0.127

Grid 1	Grid 2	Grid 3
0.137	0.155	0.154
Grid 4	Grid 5	Grid 6
0.137	0.154	0.154
Grid 7	Grid 8	Grid 9
0.131	0.132	0.128

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.154A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 824.7 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.232 A/m

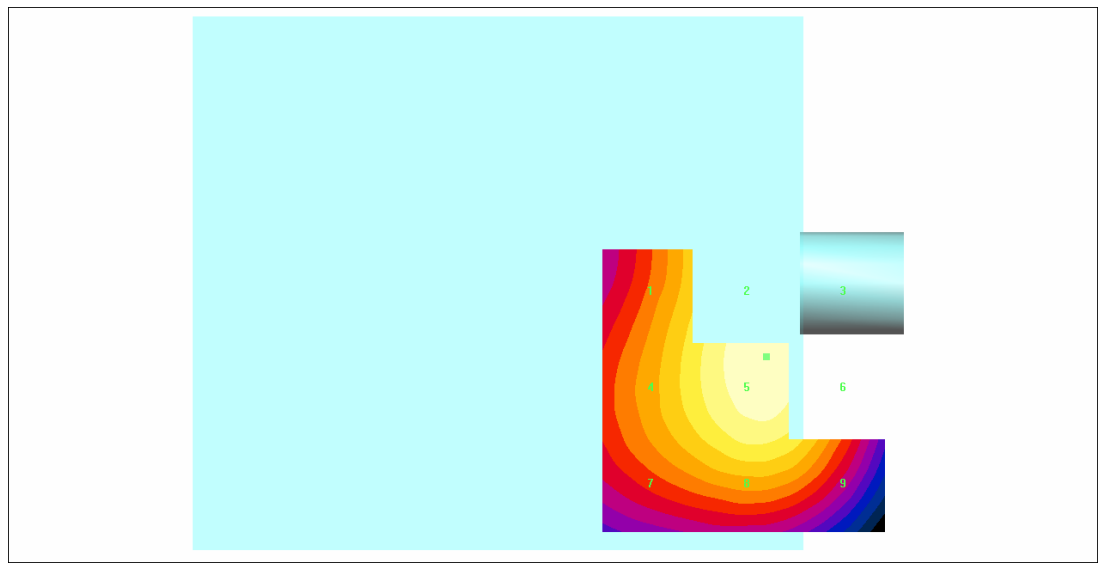
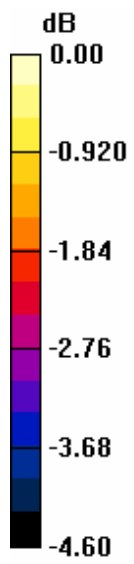
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.211	0.230	0.228
Grid 4	Grid 5	Grid 6
0.212	0.231	0.228
Grid 7	Grid 8	Grid 9
0.205	0.217	0.212

Grid 1	Grid 2	Grid 3
0.212	0.232	0.230
Grid 4	Grid 5	Grid 6
0.214	0.232	0.229
Grid 7	Grid 8	Grid 9
0.207	0.219	0.214

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.231A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 836.52 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

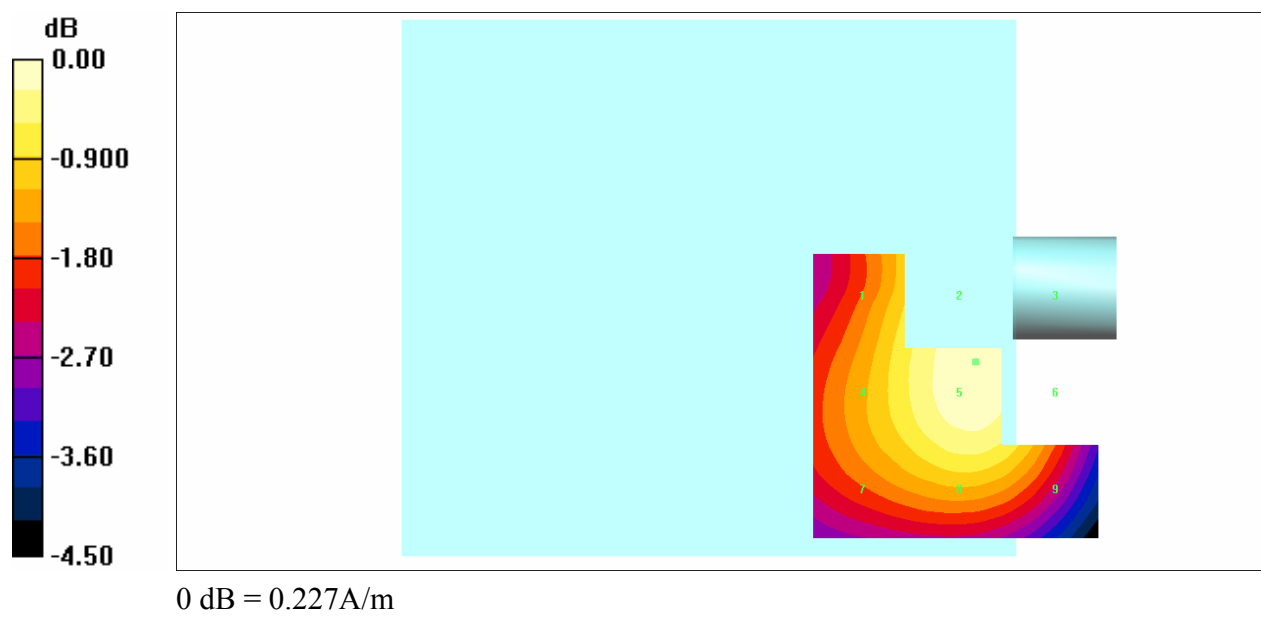
Maximum value of Total field (slot averaged) = 0.229 A/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.209	Grid 2 0.227	Grid 3 0.224	Grid 1 0.211	Grid 2 0.228	Grid 3 0.226
Grid 4 0.211	Grid 5 0.227	Grid 6 0.224	Grid 4 0.212	Grid 5 0.229	Grid 6 0.226
Grid 7 0.204	Grid 8 0.216	Grid 9 0.211	Grid 7 0.206	Grid 8 0.217	Grid 9 0.212

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA835(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: Cellular; Frequency: 848.31 MHz; Duty Cycle: 1:1.015

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

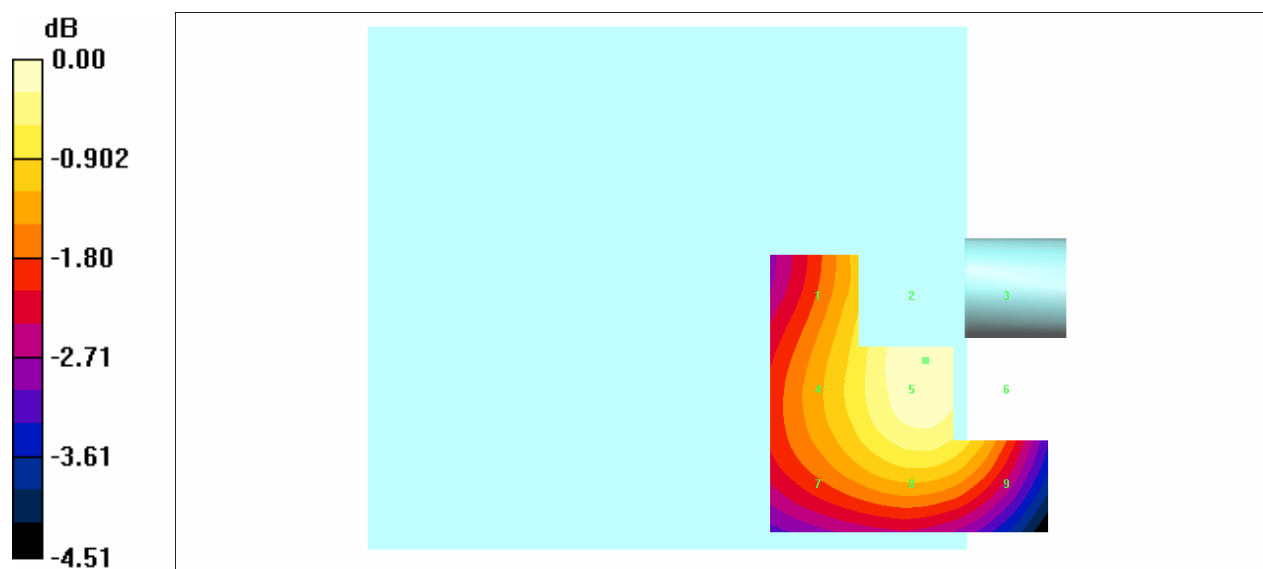
H Scan - H3DV6 probe center 10mm above Device Reference-High with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.224 A/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.203	Grid 2 0.222	Grid 3 0.218	Grid 1 0.205	Grid 2 0.223	Grid 3 0.220
Grid 4 0.205	Grid 5 0.222	Grid 6 0.218	Grid 4 0.207	Grid 5 0.224	Grid 6 0.220
Grid 7 0.200	Grid 8 0.211	Grid 9 0.206	Grid 7 0.201	Grid 8 0.213	Grid 9 0.207

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.222A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DASYS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASYS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.110 A/m

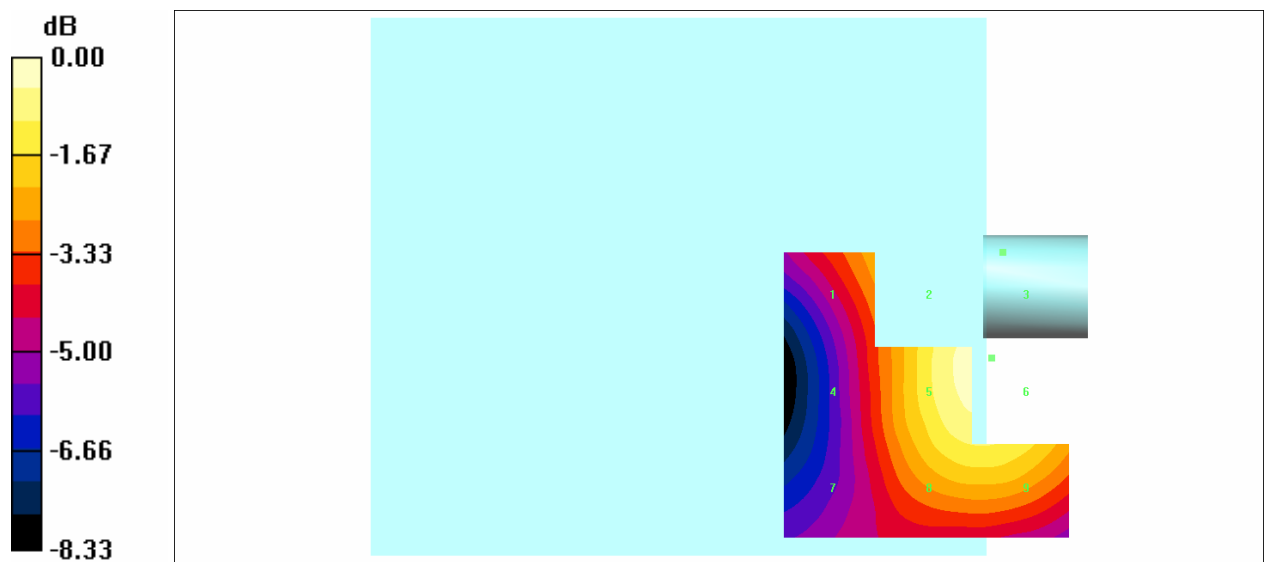
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.084	0.108	0.111
Grid 4	Grid 5	Grid 6
0.074	0.109	0.111
Grid 7	Grid 8	Grid 9
0.071	0.098	0.098

Grid 1	Grid 2	Grid 3
0.085	0.109	0.112
Grid 4	Grid 5	Grid 6
0.075	0.110	0.112
Grid 7	Grid 8	Grid 9
0.072	0.099	0.099

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.111A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.107 A/m

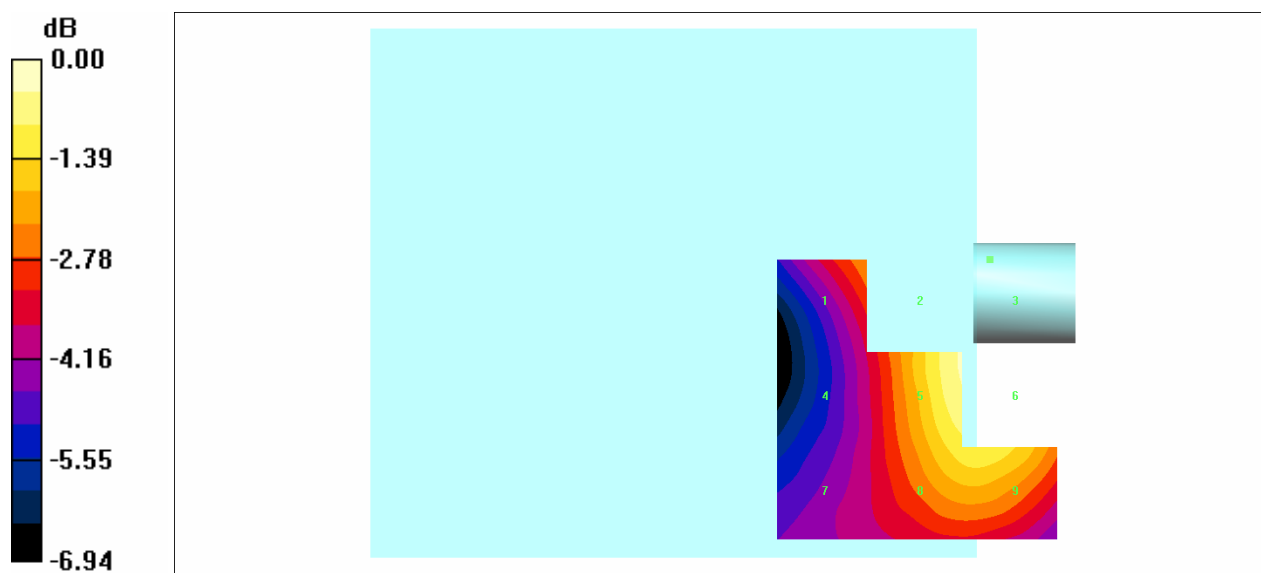
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.085	0.108	0.111
Grid 4	Grid 5	Grid 6
0.073	0.106	0.109
Grid 7	Grid 8	Grid 9
0.072	0.098	0.099

Grid 1	Grid 2	Grid 3
0.086	0.109	0.112
Grid 4	Grid 5	Grid 6
0.074	0.107	0.110
Grid 7	Grid 8	Grid 9
0.073	0.099	0.100

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.111A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-High/Hearing Aid

Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.098 A/m

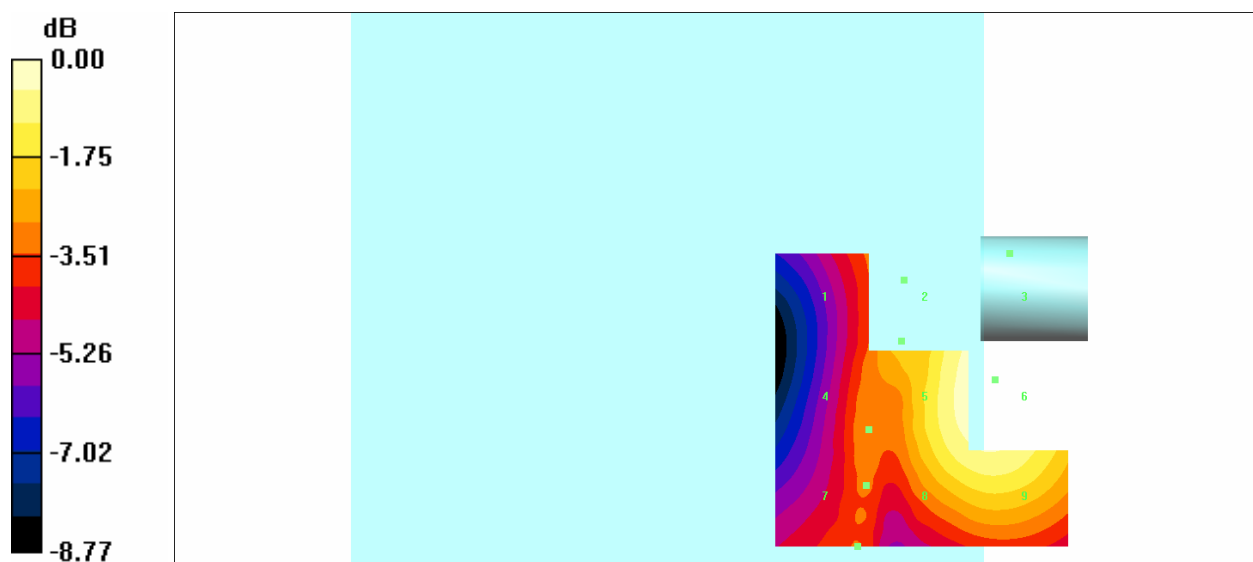
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.068	0.095	0.099
Grid 4	Grid 5	Grid 6
0.071	0.098	0.100
Grid 7	Grid 8	Grid 9
0.070	0.092	0.094

Grid 1	Grid 2	Grid 3
0.069	0.096	0.100
Grid 4	Grid 5	Grid 6
0.072	0.098	0.101
Grid 7	Grid 8	Grid 9
0.071	0.093	0.095

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1851.25 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Low with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.129 A/m

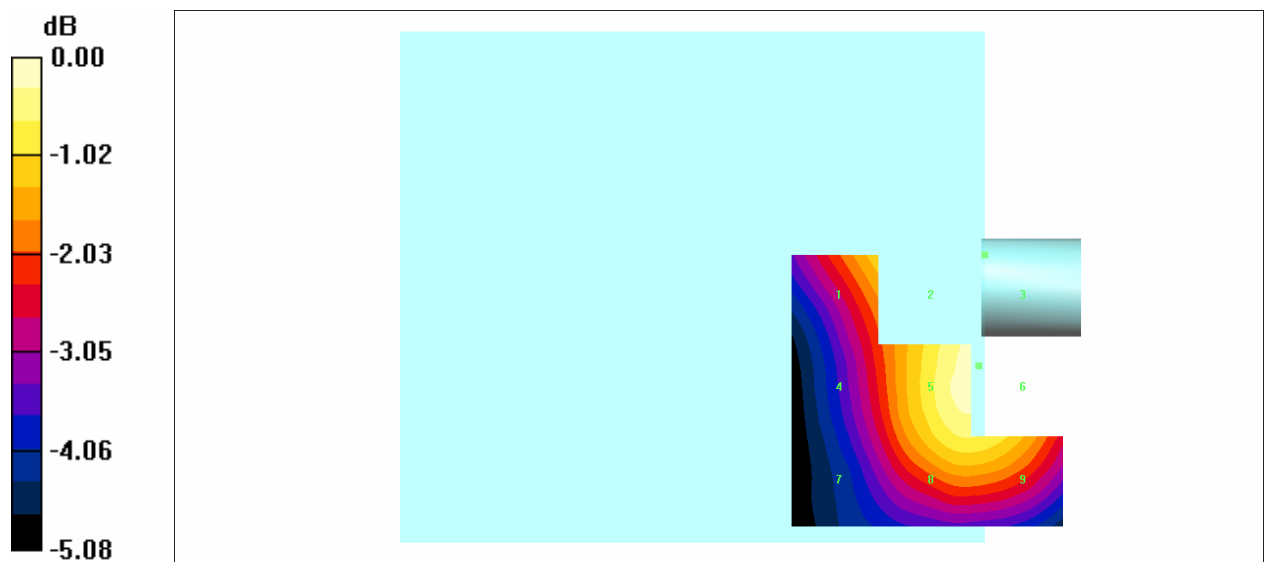
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.115	0.129	0.130
Grid 4	Grid 5	Grid 6
0.102	0.127	0.128
Grid 7	Grid 8	Grid 9
0.095	0.121	0.120

Grid 1	Grid 2	Grid 3
0.116	0.130	0.131
Grid 4	Grid 5	Grid 6
0.103	0.129	0.129
Grid 7	Grid 8	Grid 9
0.096	0.122	0.122

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.130A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1880 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-Mid with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

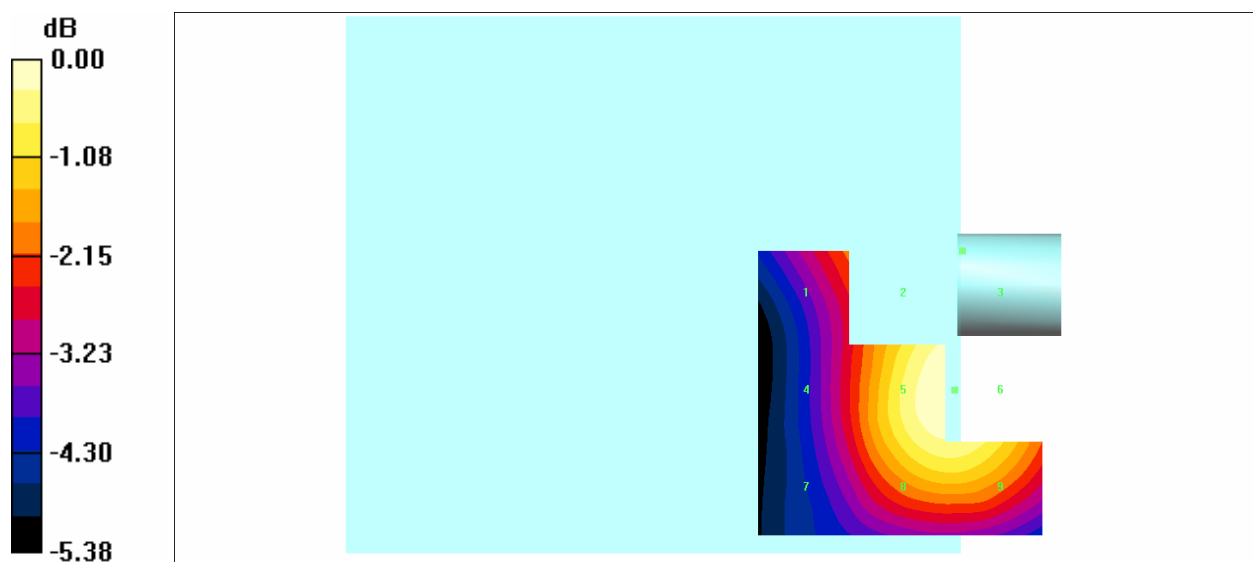
Maximum value of Total field (slot averaged) = 0.130 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.102	Grid 2 0.125	Grid 3 0.125	Grid 1 0.103	Grid 2 0.126	Grid 3 0.126
Grid 4 0.096	Grid 5 0.129	Grid 6 0.129	Grid 4 0.097	Grid 5 0.130	Grid 6 0.131
Grid 7 0.094	Grid 8 0.123	Grid 9 0.123	Grid 7 0.095	Grid 8 0.124	Grid 9 0.125

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.129A/m

Test Laboratory: Compliance Certification Services Inc.

HAC_H_SCAN_CDMA1900(open)

DUT: HTC; Type: PA10A; Serial: N/A

Communication System: CDMA PCS; Frequency: 1908.75 MHz; Duty Cycle: 1:1.018

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6163; ; Calibrated: 2005/4/27
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn558; Calibrated: 2004/8/24
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1027
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H3DV6 probe center 10mm above Device Reference-High with Co-location/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm
Maximum value of Total field (slot averaged) = 0.133 A/m

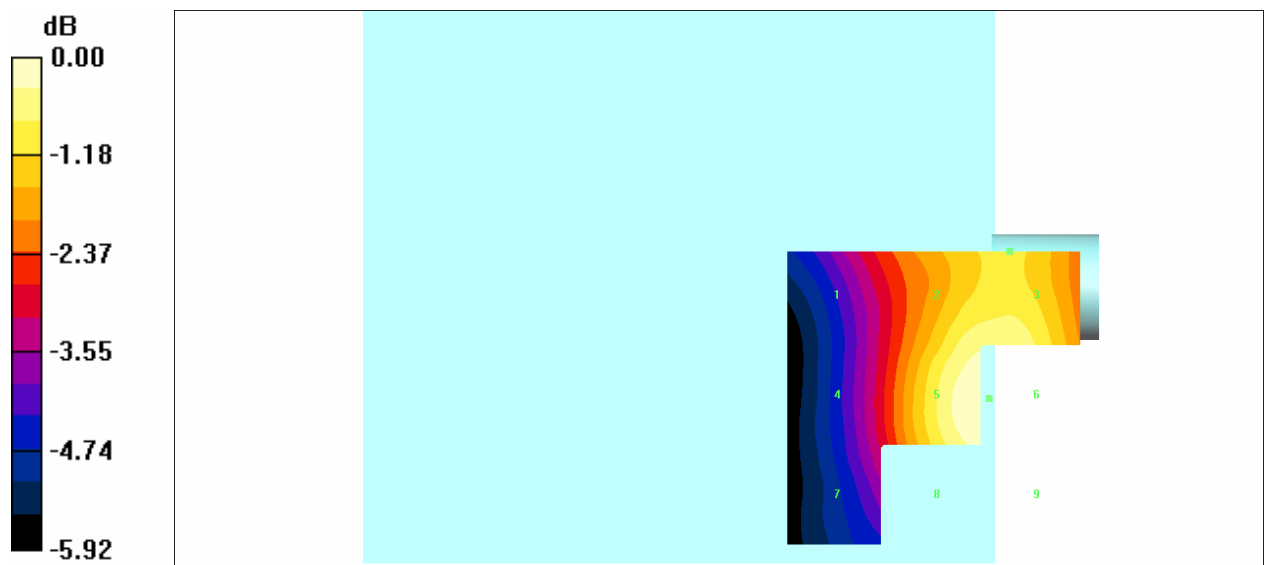
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.098	0.125	0.126
Grid 4	Grid 5	Grid 6
0.095	0.132	0.132
Grid 7	Grid 8	Grid 9
0.092	0.127	0.127

Grid 1	Grid 2	Grid 3
0.099	0.126	0.127
Grid 4	Grid 5	Grid 6
0.095	0.133	0.134
Grid 7	Grid 8	Grid 9
0.093	0.128	0.128

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.132A/m